

# Spintronic components for memories, logic and RF applications

## OUTLINE

Giant MagnetoResistance (GMR),

    Benefit in magnetic recording technology

Tunnel Magnetoresistance (TMR)

Spin-transfer

    Magnetic Random Access Memories (MRAM)

    Hybrid CMOS/MTJ components for non-volatile and reprogrammable logic

    Radio Frequency oscillators based on spin-transfer

Conclusion

# Acknowledgements



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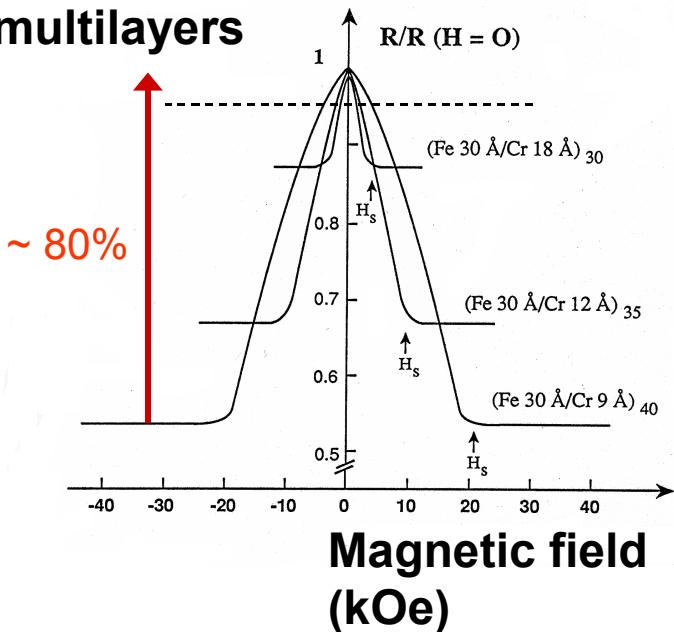


**CROCUS Technology**  
Blossoming Future



# Development of spin-electronics: strong synergy between basic research and applications

## Fe/Cr multilayers



A.Fert et al, PRL (1988); P.Grunberg et al, PRB (1989)

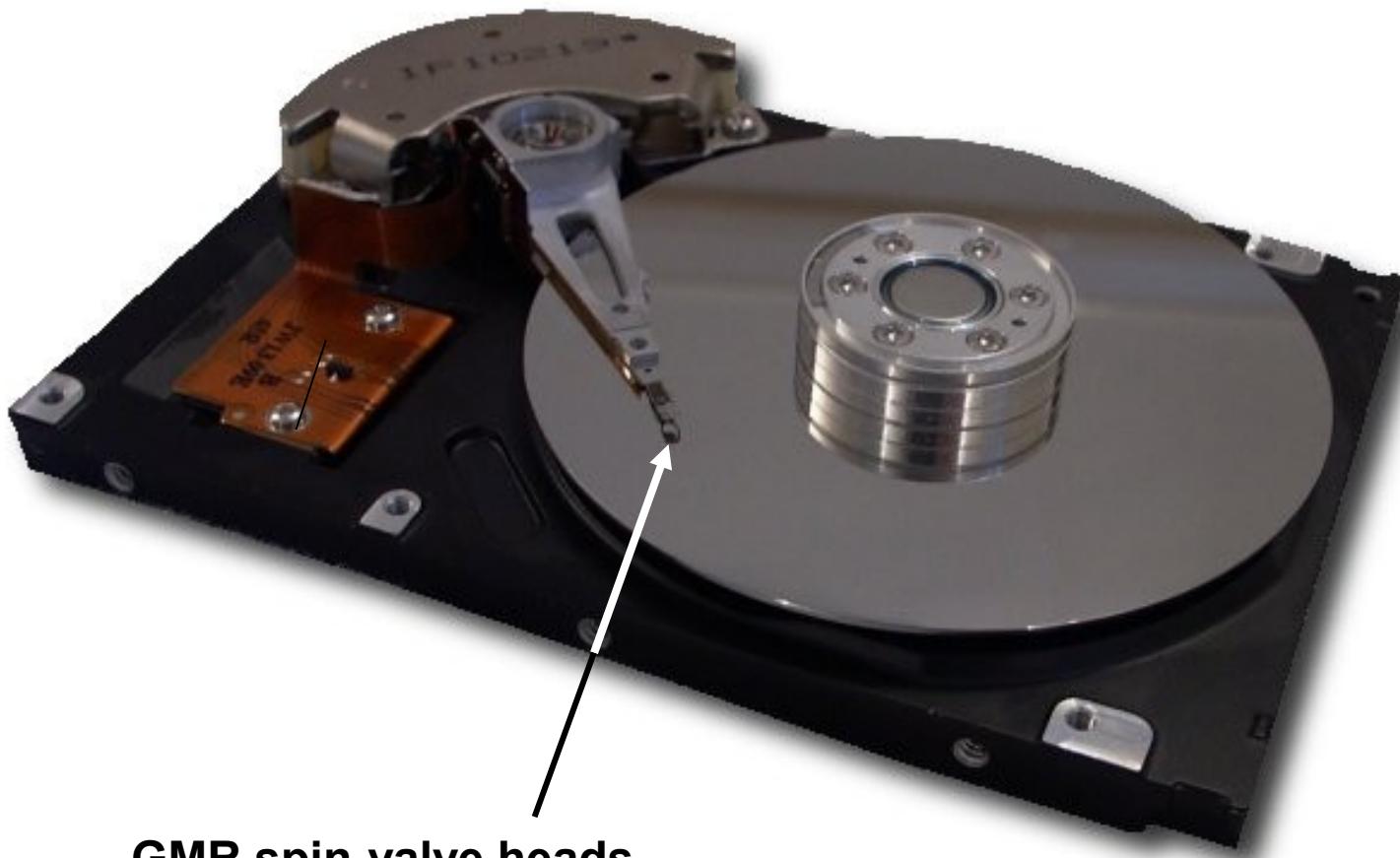
$\Delta R/R_p \sim 80\%$  at RT

Development of spintronics paved with breakthrough discoveries:

- 1) GMR  $\Rightarrow$  Hard disk drives (1990-2004)
- 2) Tunnel MR  $\Rightarrow$  MRAM, hard disk drives (1995 - ... for HDD, 2006-... for MRAM)
- 3) Spin-transfer  $\Rightarrow$  MRAM, RF oscillators

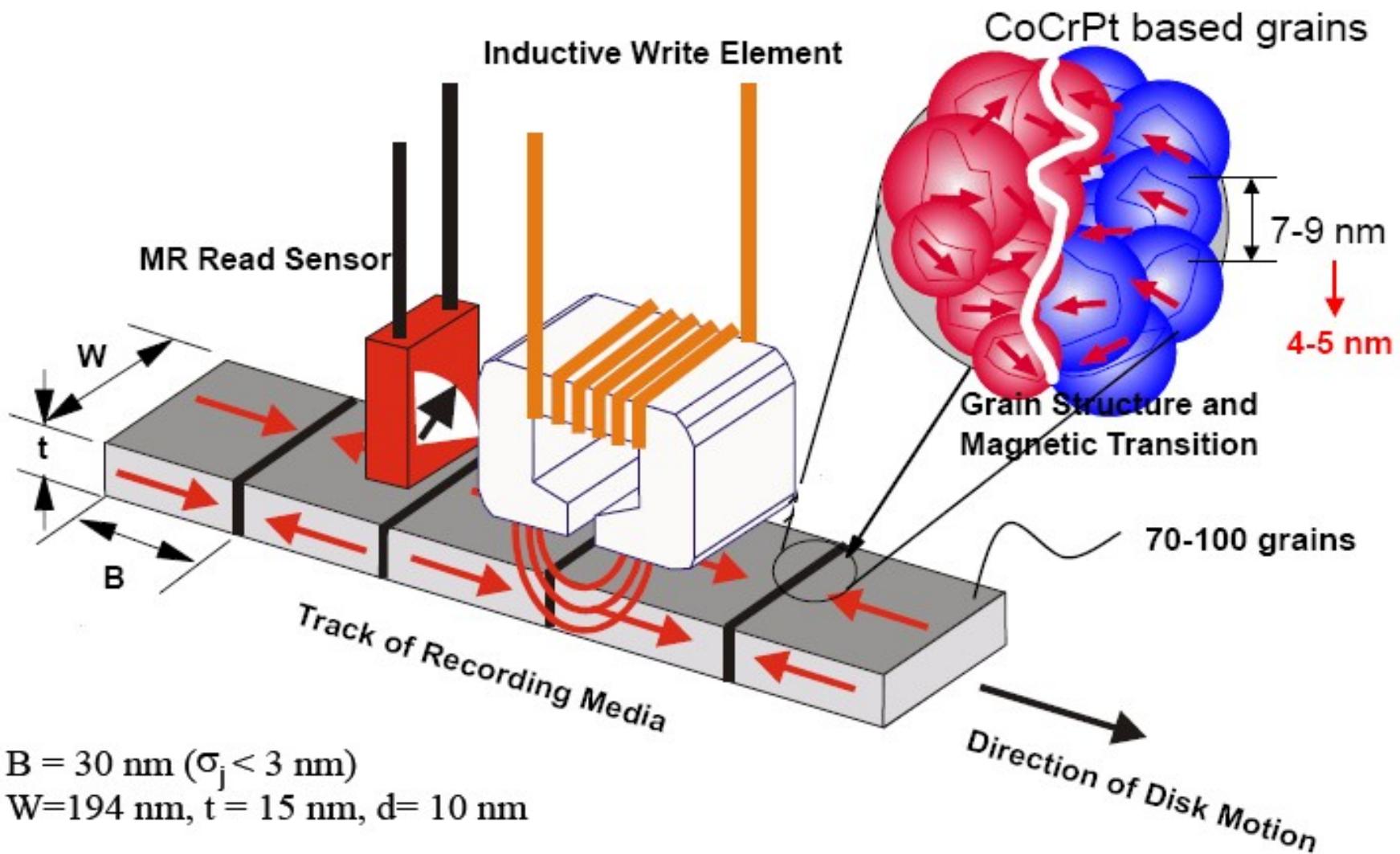
# Benefit of GMR in magnetic recording

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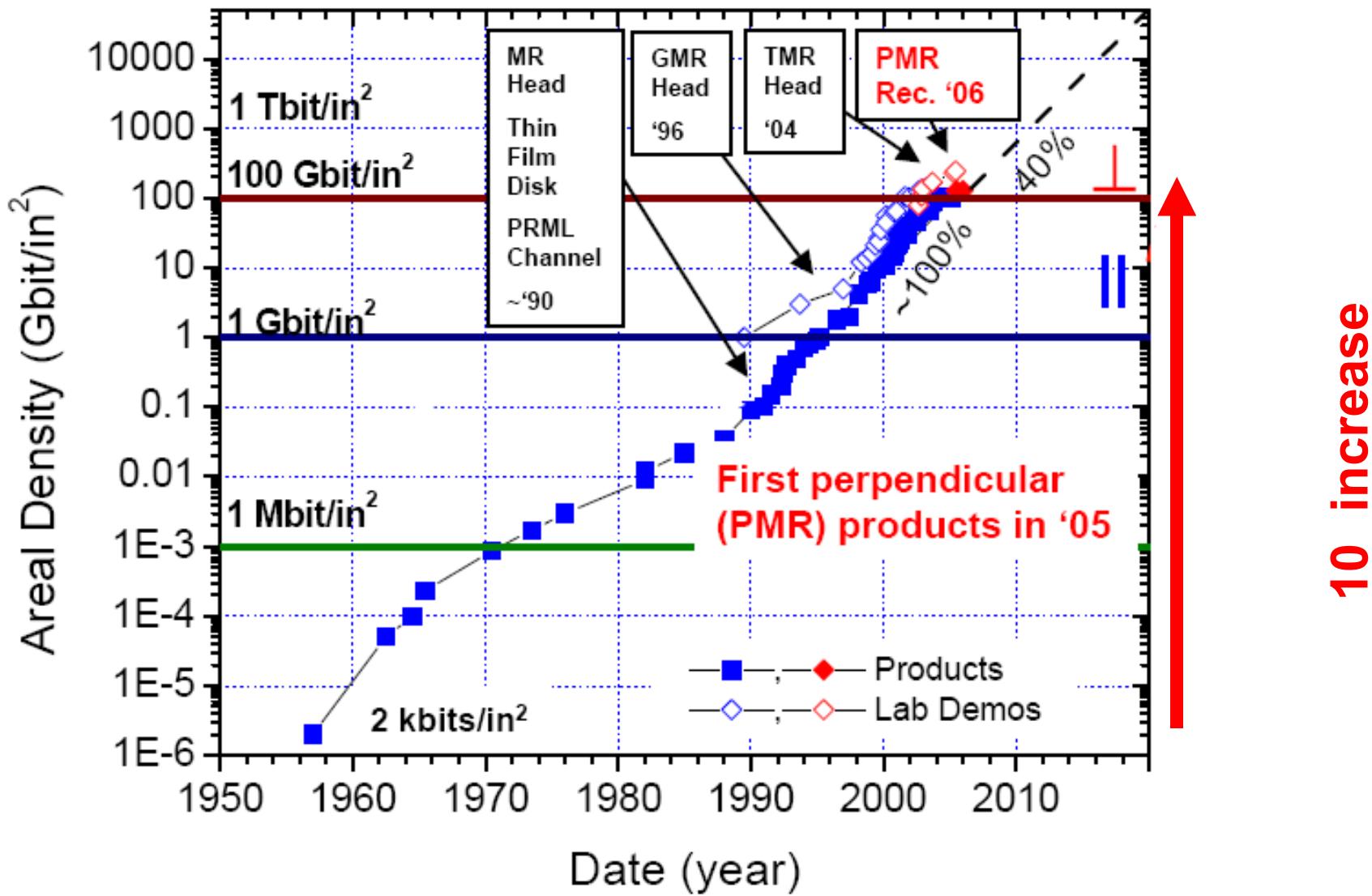


**GMR spin-valve heads  
from 1998 to 2004**

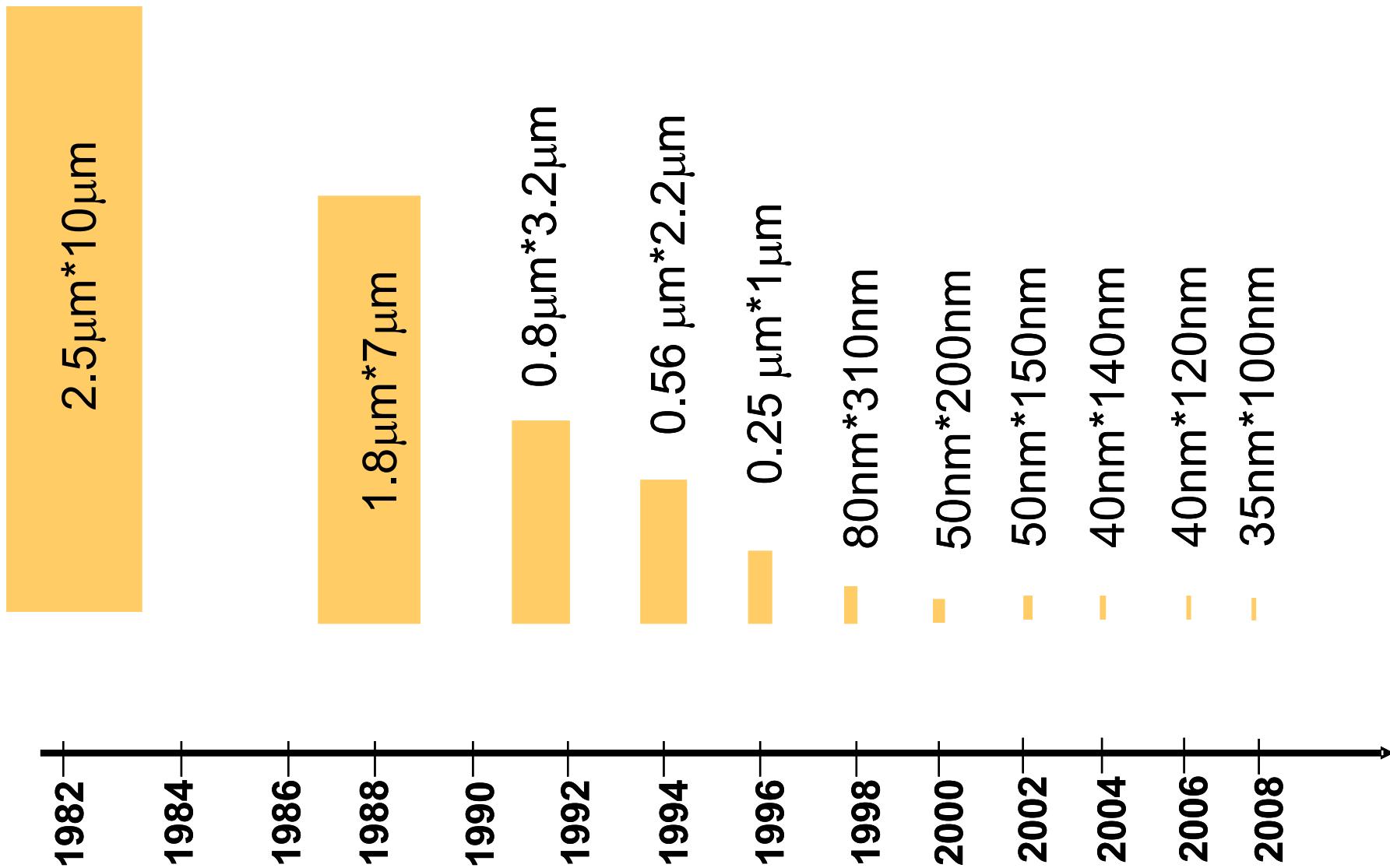
# 1) GMR in magnetic recording



# Dramatic increase in areal storage density over the past 50 years



# Evolution of magnetic bit size in hard disk drives



# Reduction in size and increase in capacity

**5 Mbyte on 50x24" disks**



**70 kbit/s**

**IBM RAMAC 1955**

**2 kbits/in<sup>2</sup>**

**50x24" dia disks**

**160 GByte on 1x3.5 "disk**

## Scaling



**436 Mbit/s**

**Seagate U series 2001**

**32.6 Gbits/in<sup>2</sup>**

**2 x 3.5"glass disks**

**At 1 Tbit/in<sup>2</sup> ~600 Gbyte  
per 2.5" platter**



**Seagate (1")**

**340 Mbyte >12 Gbyte**



**Seagate ST1.3 (1")**

**160.000 Kbit/s**

**Seagate ST1.3**

**130 Gbits/in<sup>2</sup>**

**1 x 1" dia disk**

Areal storage density: +60%/year

# New applications of HDD made possible thanks to miniaturization



GMR spin-valve heads  
from 1998 to 2004



## 2) Magnetic tunnel junctions

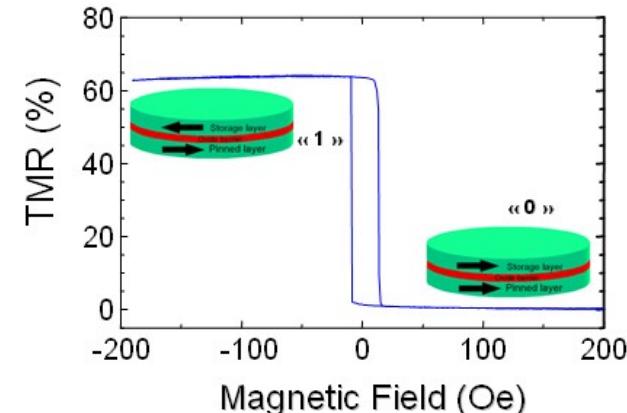
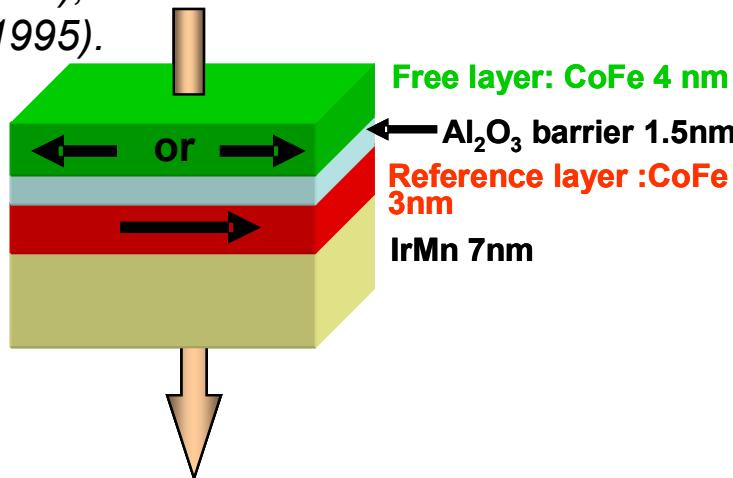
**Tunnel magnetoresistance at 300K in amorphous Alumina based MTJ:**

Julliere (1975) but at low T only

Moodera et al, PRL (1995);

Myazaki et al, JMMM(1995).

TMR~40-70%



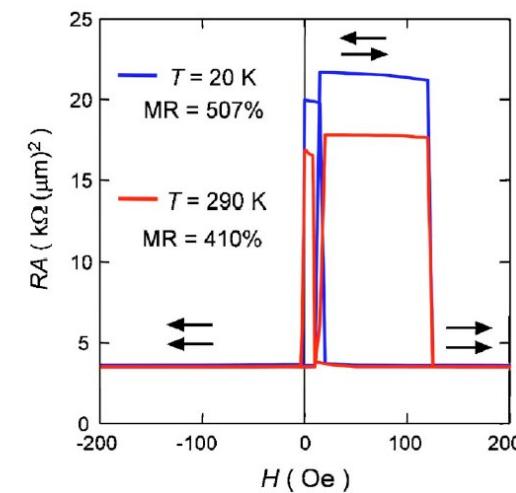
**« Giant » tunnel magnetoresistance at RT in crystalline MgO based MTJ:**

Parkin et al, Nature Mat. (2004);

Yuasa et al, Nature Mat. (2004).

TMR~200-500%

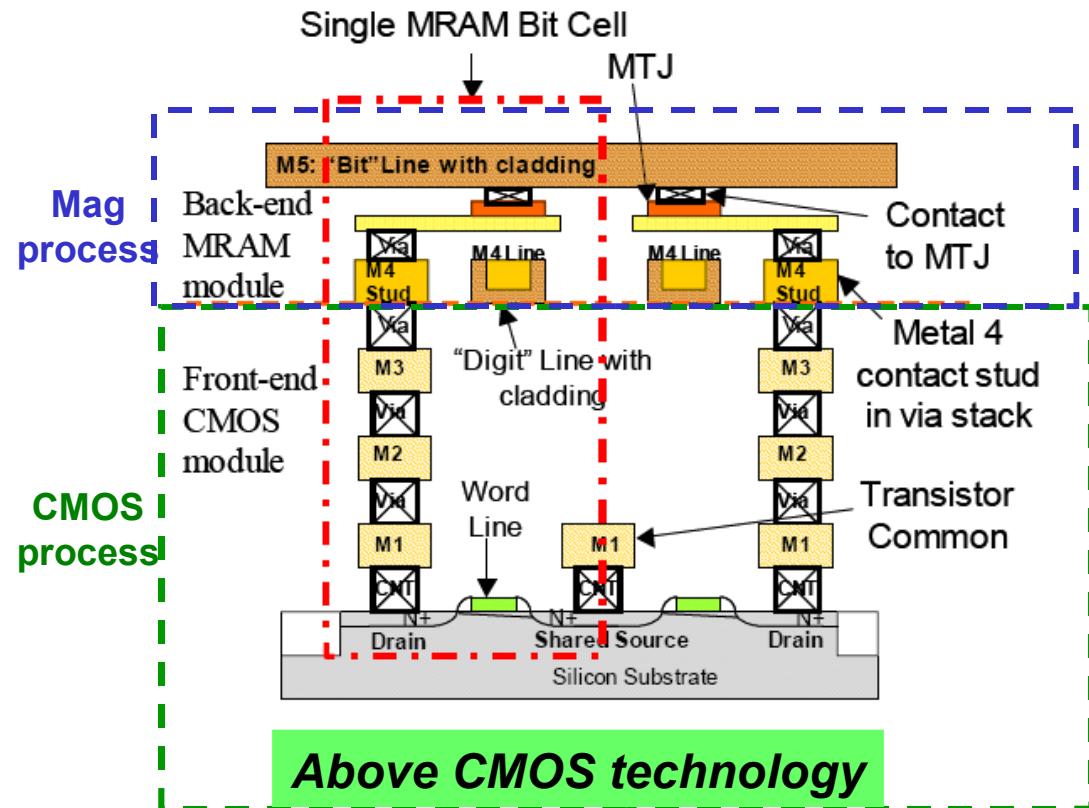
Au cap 50 nm
Ir-Mn 10 nm
Fe(001) 10 nm
Co(001) 0.57 nm
MgO(001) 2.2 nm
Co(001) 0.57 nm
Fe(001) 100 nm
MgO(001) 20 nm
MgO(001) sub.



# Magnetic Tunnel Junctions (MTJ): a new path for CMOS/magnetic integration



- Resistance of MTJ compatible with resistance of passing FET (few  $k\Omega$ )
- MTJ can be deposited in magnetic back end process
- No CMOS contamination
- MTJ used as variable resistance controlled by field or current/voltage (Spin-transfer)



Cross-section of Freescale 4Mbit MRAM based on field switching

### 3) Spin-transfer

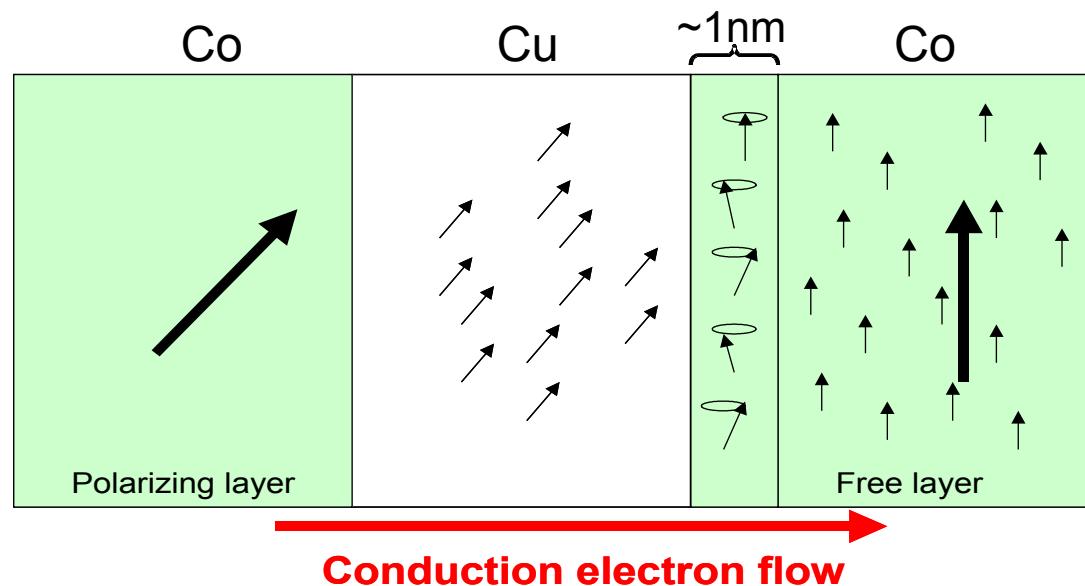
Predicted by Slonczewski (JMMM.159, L1(1996)) and Berger (Phys.Rev.B54, 9359 (1996)),

#### Giant or Tunnel magnetoresistance:

Acting on electrical current via the magnetization orientation

#### Spin transfer is the reciprocal effect:

Acting on the magnetization via the spin polarized current



M.D.Stiles et al,  
Phys.Rev.B.66,  
014407 (2002)

Reorientation of the direction of polarization of current via incoherent precession/relaxation of the electron spin around the local exchange field



Torque on the Free layer magnetization

# Magnetization dynamics: Effective field + spin-torque

Slonczewski (JMMM.159, L1(1996)) and Berger (Phys.Rev.B54, 9359 (1996)), Stiles, Levy, Fert, Barnas, Vedyayev

$$\frac{dM}{dt} = -\gamma M \times (H_{eff} + bI.M_p) + \gamma a I.M \times (M \times M_p) + \alpha M \times \frac{dM}{dt}$$

Effective field term (conserve energy)

Spin-torque term: damping (or antidamping) term

Polarizer  $M$

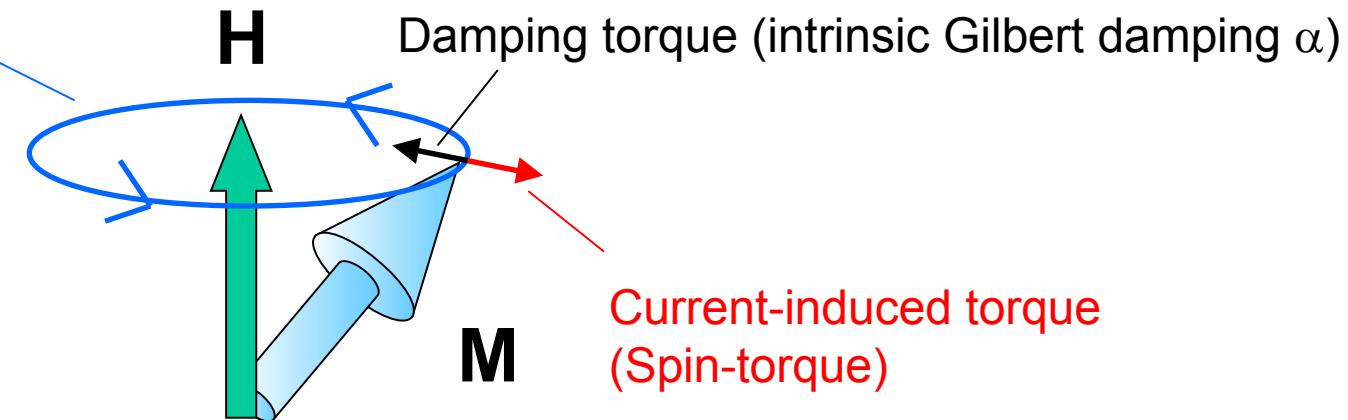
Gilbert Damping term

Non conservative

( Modified LLG)

a and b are coefficients proportional to the spin polarization of the current

Precession from effective field



Effective field term seems weak in metallic pillars (<10% of spin-torque term) but more important in MTJ (~30% of spin-torque term)

# Energy dissipation and energy pumping due to spin transfer torque

Without spin torque (standard LLG)  $\frac{dE}{dt} = -\frac{\alpha\gamma}{1+\alpha^2} \frac{1}{M_s} |\mathbf{H}_{eff} \times \mathbf{M}|^2 < 0$

Dissipation, leading to relaxation towards effective field

Z.Li and S.Zhang,  
Phys.Rev.B68, 024404 (2003)

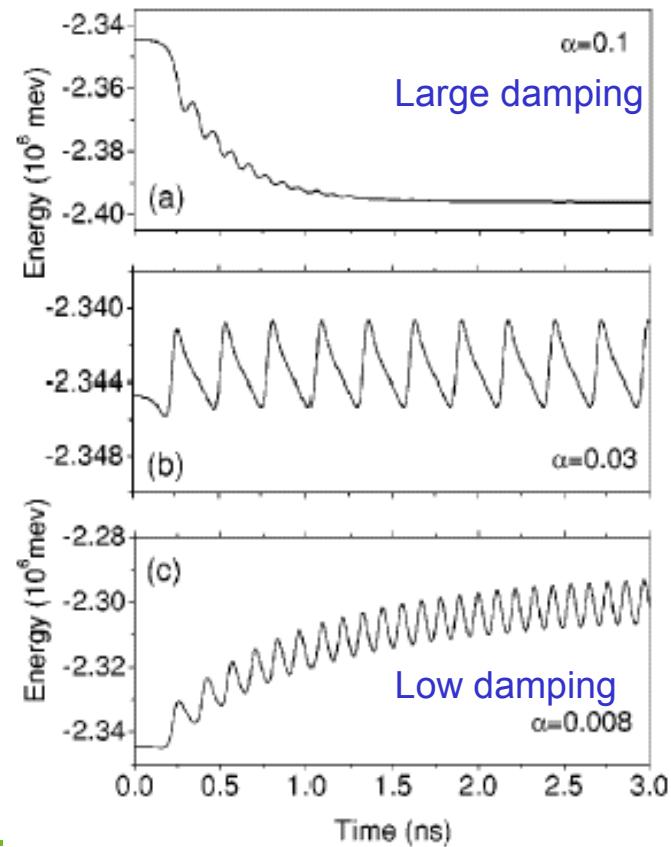
With spin torque term :

$$\frac{dE}{dt} = -\frac{\gamma}{1+\alpha^2} \frac{1}{M_s} [\alpha |\mathbf{H}_{eff} \times \mathbf{M}|^2 - a_J (\alpha M_s \hat{\mathbf{M}}_p - \mathbf{M} \times \hat{\mathbf{M}}_p) \times (\mathbf{H}_{eff} \times \mathbf{M})],$$

$dE/dt$  can be either  $>0$  or  $<0$

With Large damping: standard dynamical behavior,

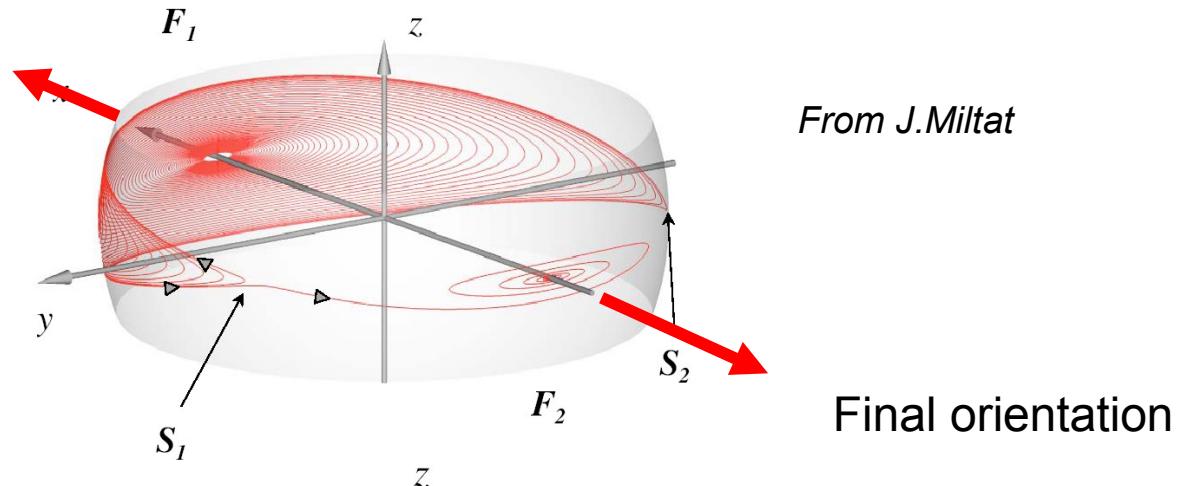
With low damping: New dynamical effects such as spin current induced excitations



# Current induced switching: Macrospin approximation

Initial orientation

Polarisation of spin-current



From J.Miltat

Three steps:

- Increase in precession angle
- switching in the opposite hemisphere
- fast relaxation

Analysis of stability of LLG equation : initial state becomes unstable for

$$(a_J)_{crit} = \pm \alpha (2\pi M_s + H_K) + \alpha H_{ext} \approx \alpha 2\pi M_s$$

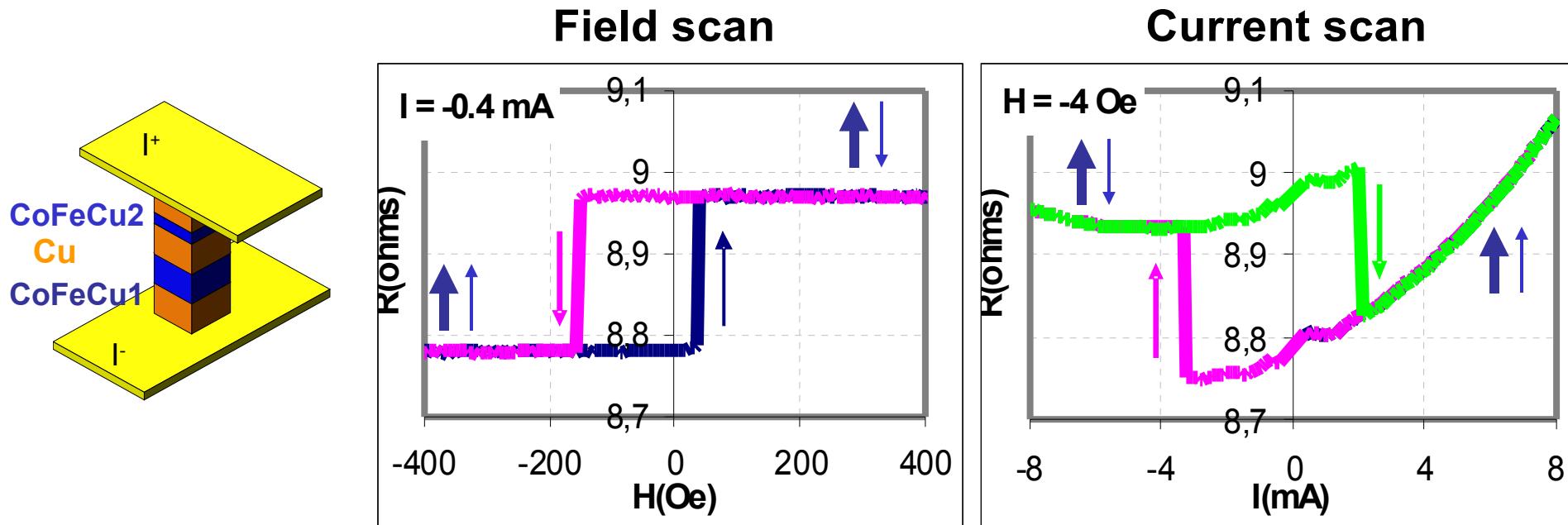
Where  $a_J$  is prefactor of ST term:

$$(a_J) = -\frac{|g|}{2} \frac{\mu_B}{M_s^2} \frac{1}{d} \frac{J}{e} P$$

Switching of a 2.5nm Co layer  
for  $j \sim 2-4 \cdot 10^7 \text{ A/cm}^2$

# Magnetization switching induced by a polarized current

Katine et al, Phys.Rev.Lett.84, 3149 (2000) on Co/Cu/Co sandwiches ( $J_c \sim 2-4.10^7 A/cm^2$ )

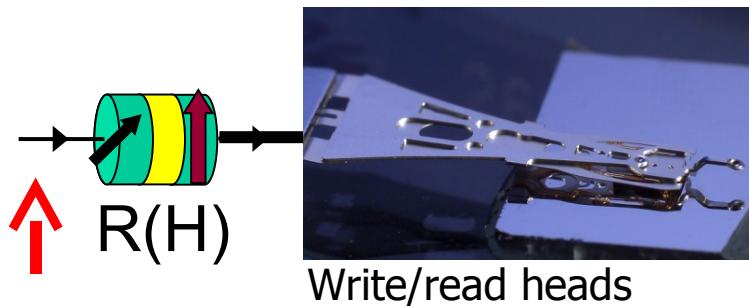


$$j_c^{P-AP} = 1.9 \cdot 10^7 A/cm^2$$

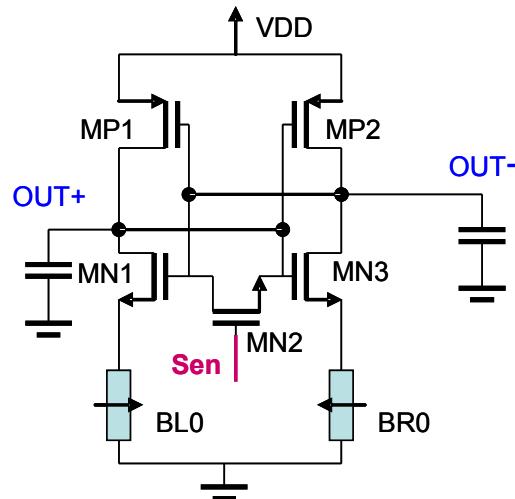
$$j_c^{AP-P} = 1.2 \cdot 10^7 A/cm^2$$

By spin transfer, a spin-polarized current can be used to manipulate the magnetization of magnetic nanostructures instead of by magnetic field.  
⇒ Can be used as a **new write scheme in MRAM**  
⇒ Or to generate steady state oscillations leading to **RF oscillators**

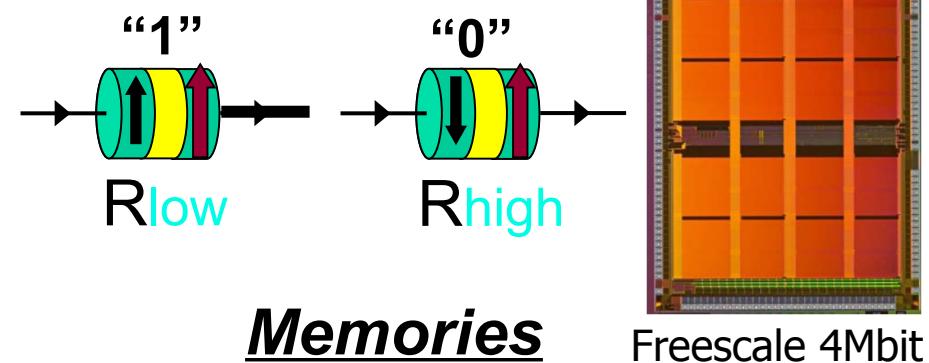
# Spintronic components



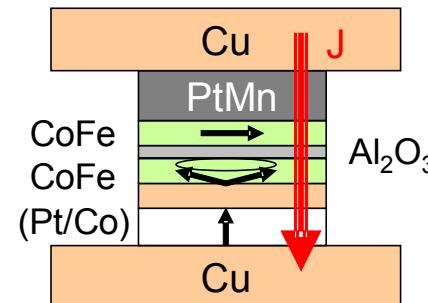
## Magnetic field sensors



## Logic circuits



## Memories



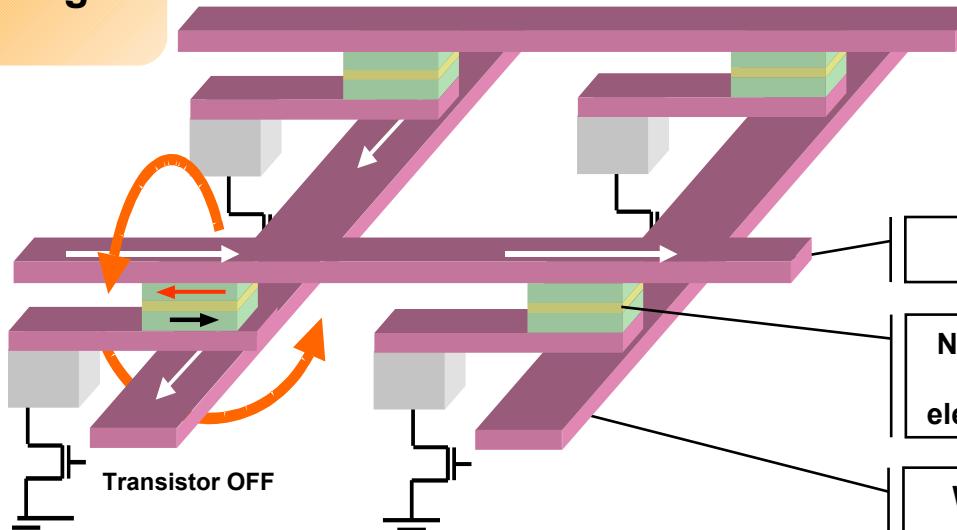
## RF components

# Field induced magnetic switching (FIMS) MRAM

## Principle :

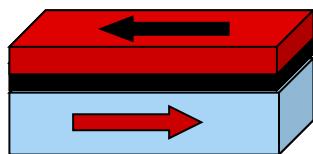
Store data by the direction (parallel or antiparallel) of magnetic layers in MTJ

## Writing



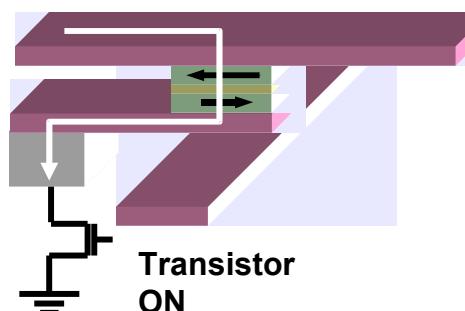
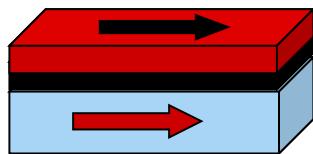
Selectivity achieved by combination of two perpendicular magnetic fields

"1"



## Reading

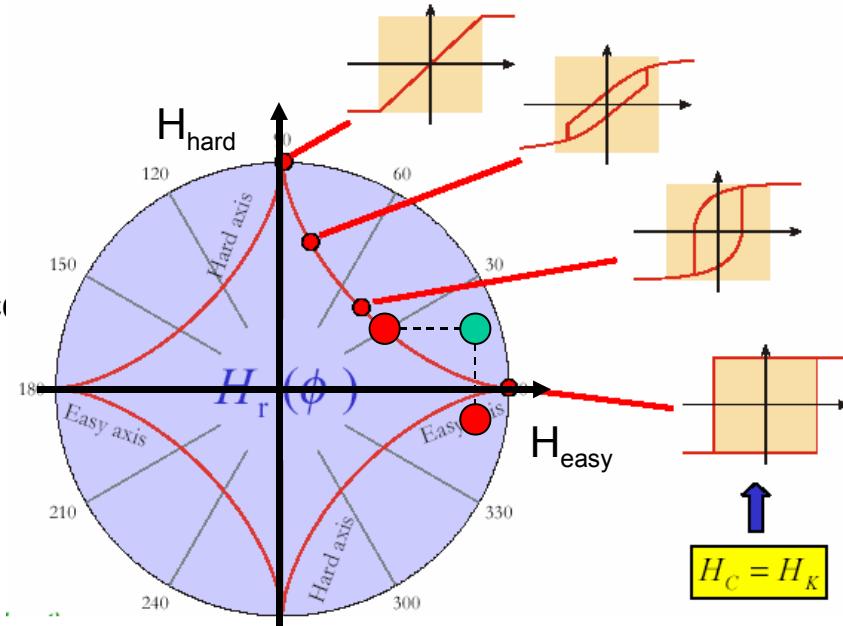
"0"



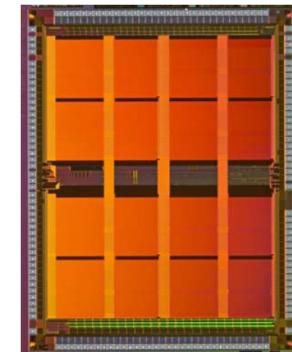
# Field induced switching MRAM Write Operation

## Stoner-Wohlfarth switching

- Selectivity based on Astroid diagram
  - With proper adjustment of  $H_x$  and  $H_y$ , only the cell simultaneously submitted to  $H_x$  and  $H_y$  switches, and not the half selected cell
  - Requires narrow distributions of switching field
- manufacturing issues



4Mbit product from FREESCALE launched in 2006.  
Great achievement which demonstrates that CMOS/MTJ integration is possible in a manufacturable process.



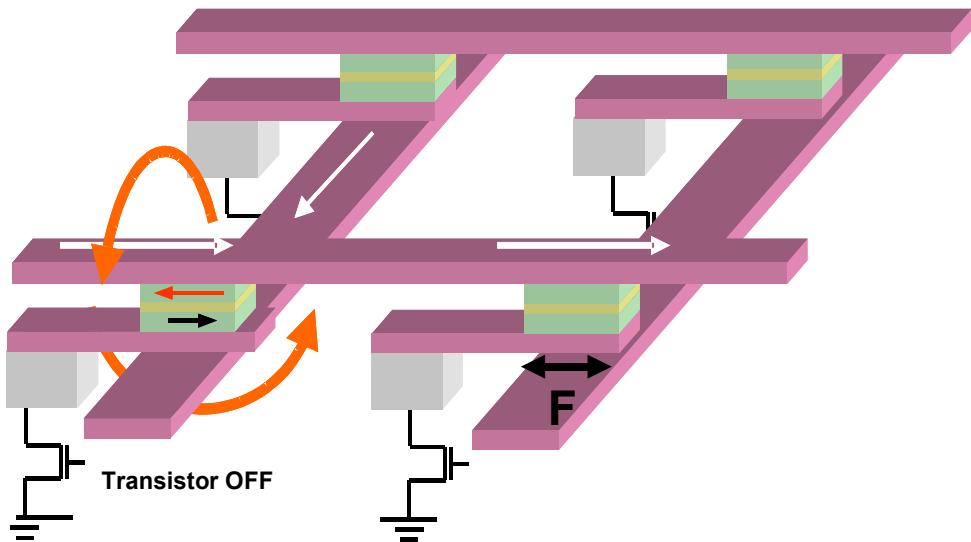
However,

High power consumption as large magnetic fields ( $\sim 50\text{-}70\text{ Oe}$ ) required for switching:  $I \sim 5\text{ mA/Line}$ .

Power consumption will increase upon scaling down due to increasing shape anisotropy necessary for thermal stability.

Freescale 4Mbit

# Poor scalability of field induced switching MRAM



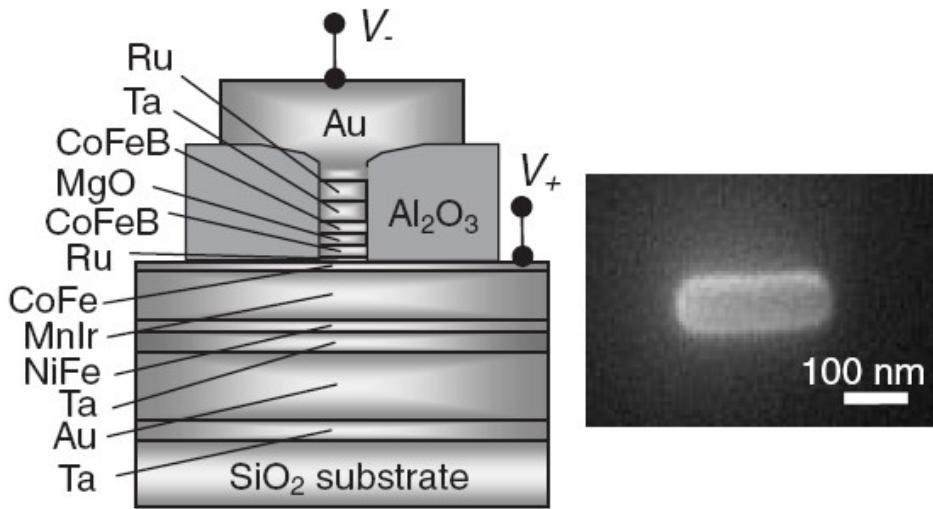
Limited scalability due to  
electromigration in bit/word lines

# Solution 1: Spin-Transfer Torque MRAM

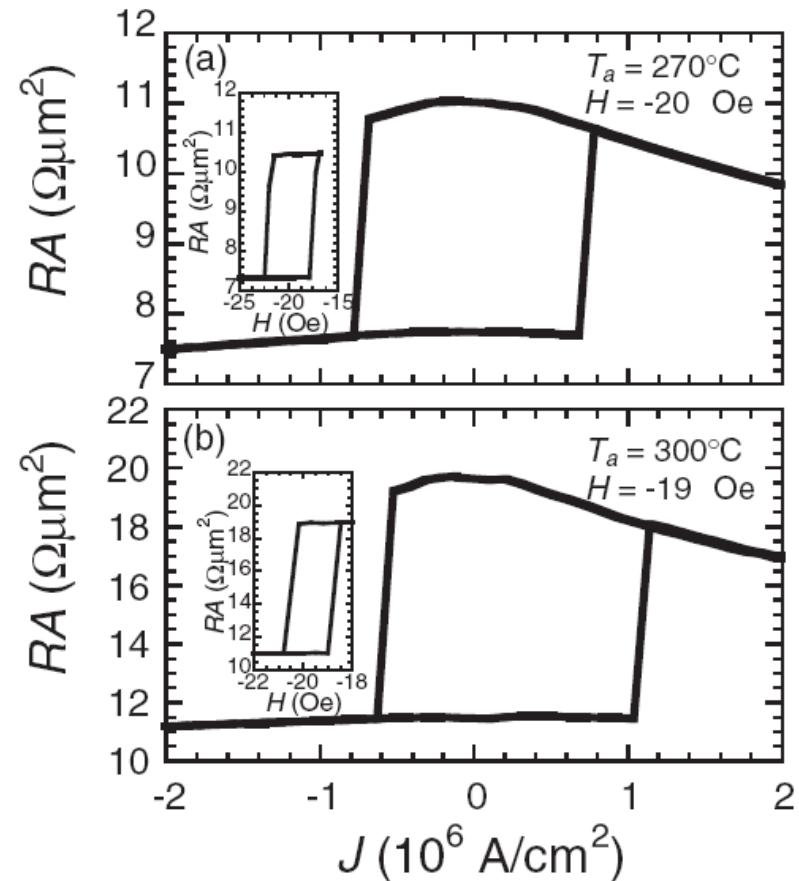
Slonczewski, Berger (1996); STT in MTJ: Huai et al, APL (2004); Fuchs et al, APL (2004)

The bipolar current flowing through the MRAM cell is used to switch the magnetization of the storage layer.

Reading at lower current density than writing so as to not perturb the written information while reading.

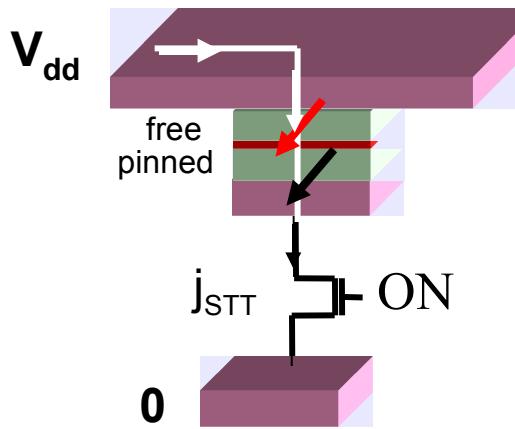


**Hayakawa et al,**  
Japanese Journal of Applied Physics  
44, (2005), L 1267

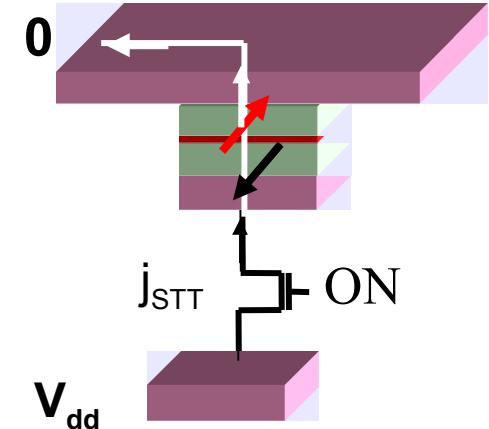


# STT MRAM scalability

Writing “0”



Writing “1”



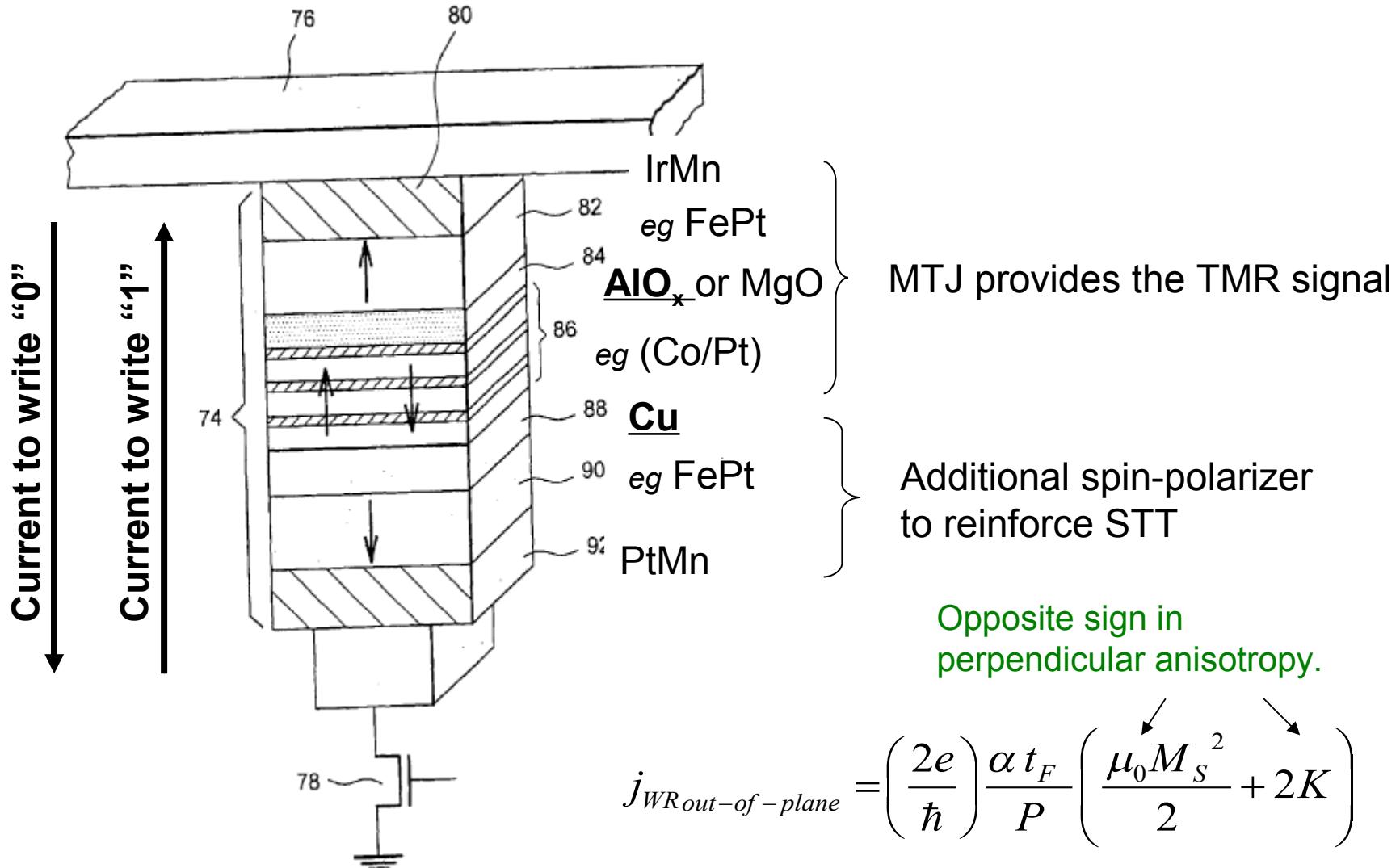
- Writing determined by a current density : 
$$j_{WRin-plane} = \left( \frac{2e}{\hbar} \right) \frac{\alpha t_F}{P} \left( \frac{\mu_0 M_S^2}{2} + 2K \right)$$
- Current through cell proportional to MTJ area

Huai et al, Appl.phys.Lett.87, 222510 (2005) ; Hayakawa, Jap.Journ.Appl.Phys.44 (2005) L1246

- Concern with thermal stability of the cell below 45nm (superparamagnetic limit)
  - Increasing aspect ratio inefficient for AR>2 (nucleation/propagation)
  - Increasing intrinsic anisotropy often increases Gilbert damping

# Perpendicular-to-plane STT MRAM

FR2832542 filed 16th Nov.2001, US6385082

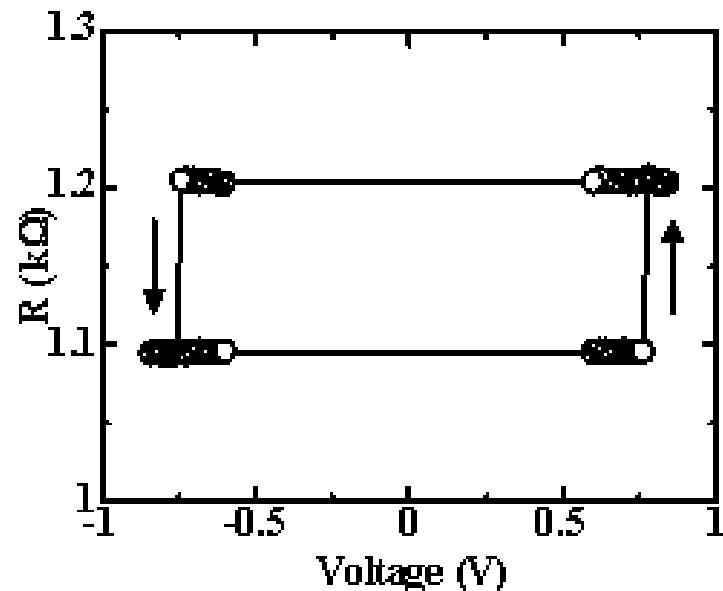
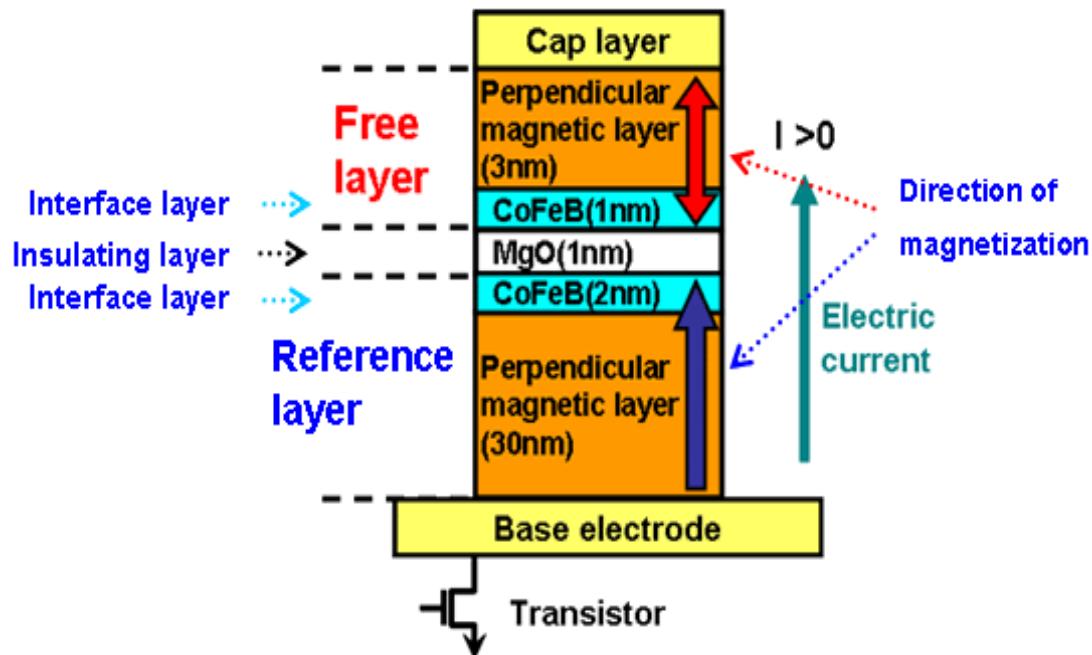


Switching current can be lower than with in-plane magnetized material

# Perpendicular-to-plane STT MRAM

Toshiba develops new MRAM device which opens the way to giga-bits capacity [www.toshiba.co.jp/about/press/2007\\_11/pr0601.htm](http://www.toshiba.co.jp/about/press/2007_11/pr0601.htm)

06 November, 2007



$$j_c \sim 3.10^6 \text{ A/cm}^2$$

$$j_{WRout-of-plane} = \left( \frac{2e}{\hbar} \right) \alpha t_F \left( \cancel{\frac{\mu_0 M_s^2}{2}} + 2K \right)$$

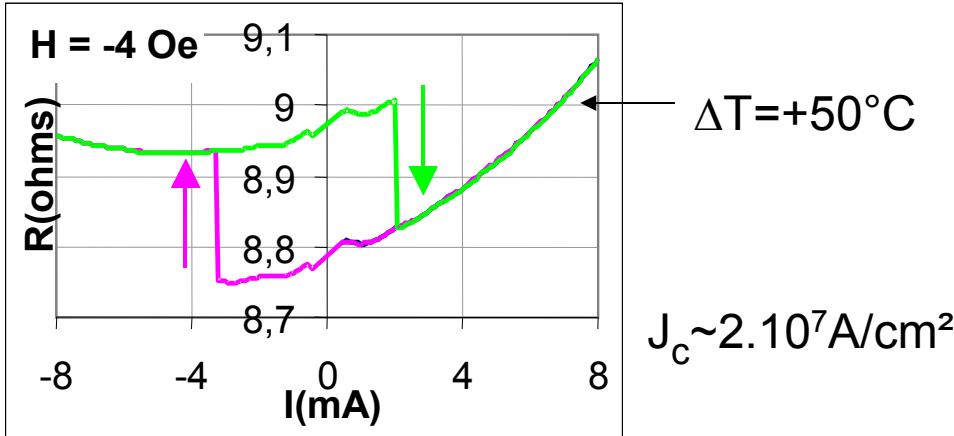
Ability to maintain low  $\alpha/P$  factor with out-of plane anisotropy (?)

# Heating effects in STT cells

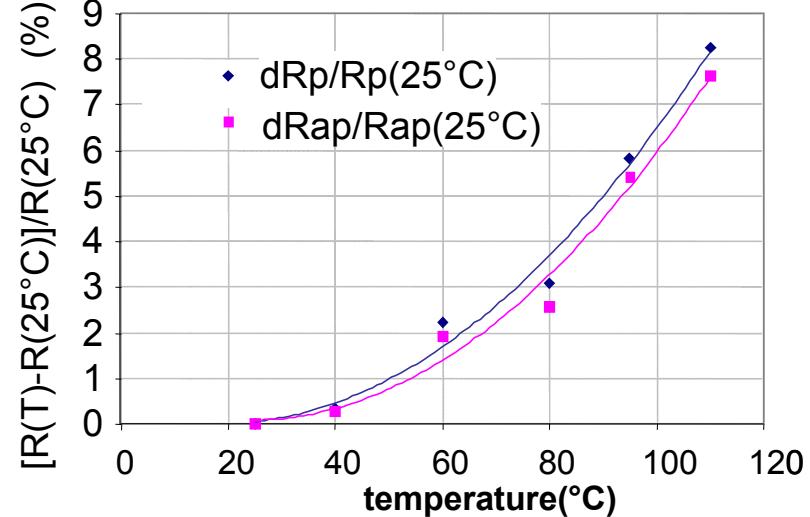
Heating does take place in metallic and MTJ cells during STT writing

NiFe/Ta5nm/IrMn 7nm/CoFe3nm/Ru0.6nm/CoFeCu2.5nm/Cu3nm/CoFeCu3nm/Ta5nm/Cu

## CPP SV:



Deac et al, Phys. Rev. B73 (6), 064414  
'2006)



## MTJ:

$$P_{heating} = RA \cdot j^2$$

10 times lower  $j_c$  than in CPP SV but  $>10^3$ \* higher RA

so that comparable or even larger heating power in MTJ than in metallic CPP SV.

**Stochastic switching + Possible drift in temperature upon repeated write**

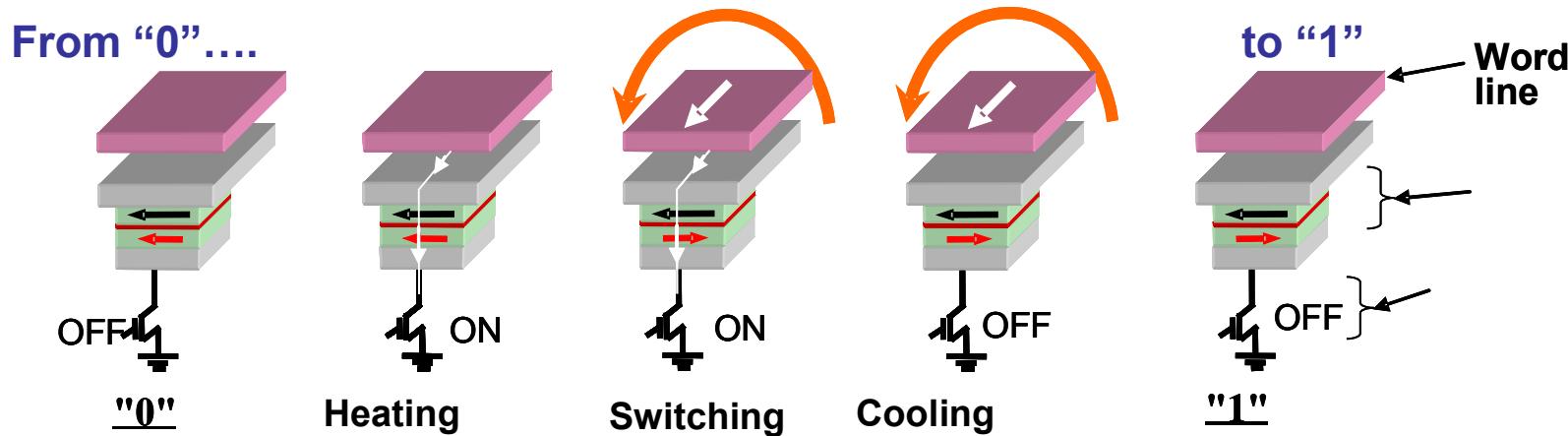
## Solution 2 : Thermally assisted MRAM

Very similar to Heat Assisted Magnetic Recording (HAMR)

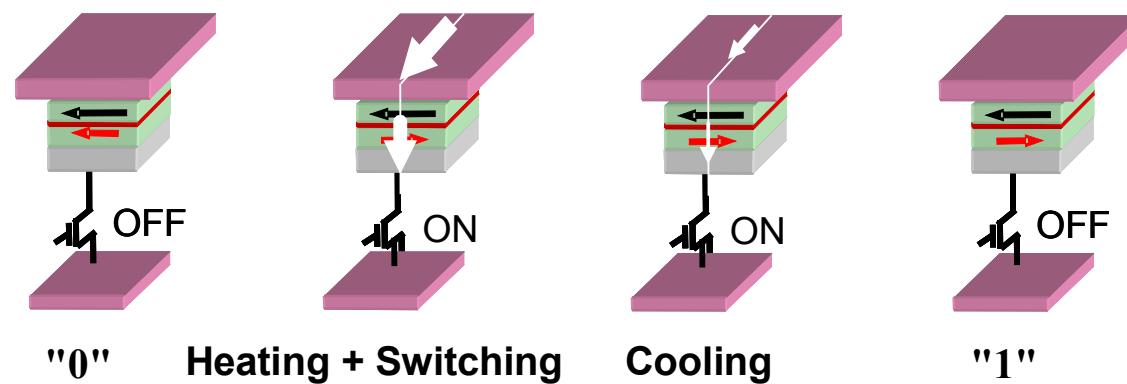
Write at elevated temperature – Store at room temperature

In TA-MRAM: Heating by current flowing through the cell

Heating+ pulse of magnetic field:



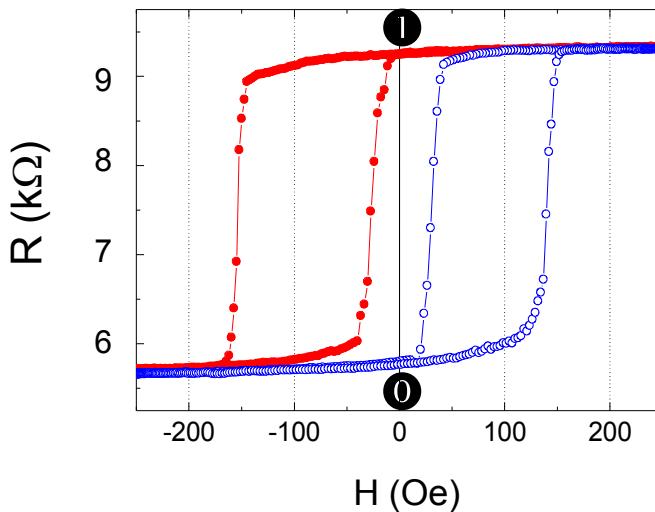
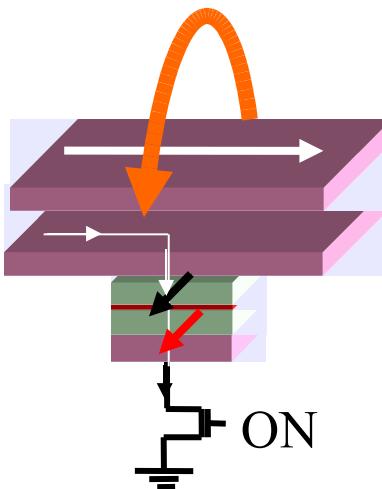
Heating + STT:



FR2832542 filed 16th Nov.2001, US6385082

# Thermally assisted writing in TA-MRAM

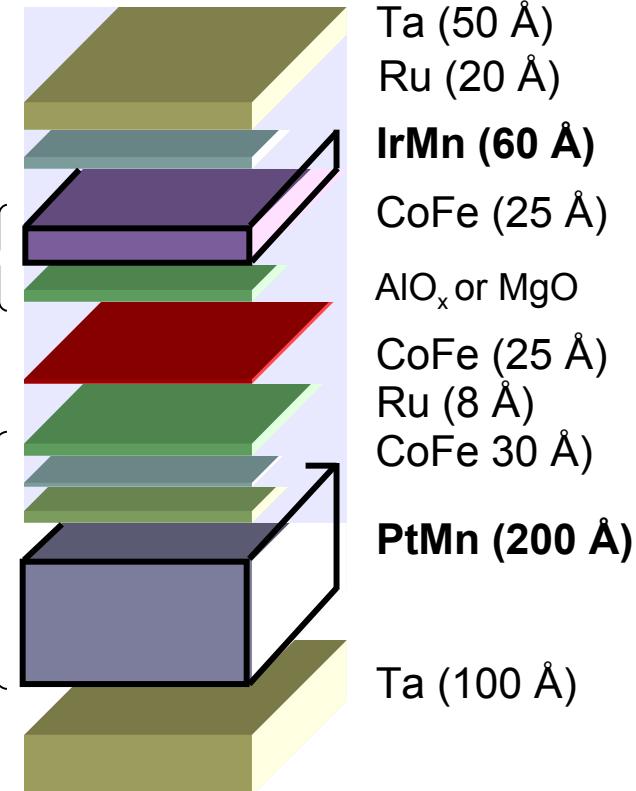
Heating  
+  
Field  $\sim 2.5\text{mT}$



## Exchange biased storage layer

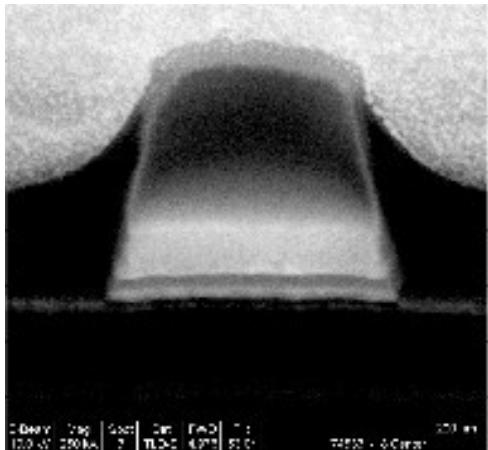
Storage  
Low  $T_B$   
 $\sim 160^\circ\text{C}$

Reference  
High  $T_B$   
 $\sim 300^\circ\text{C}$



➤ heat the storage layer above the low  $T_B$

# Heating Dynamics in TA-MRAM



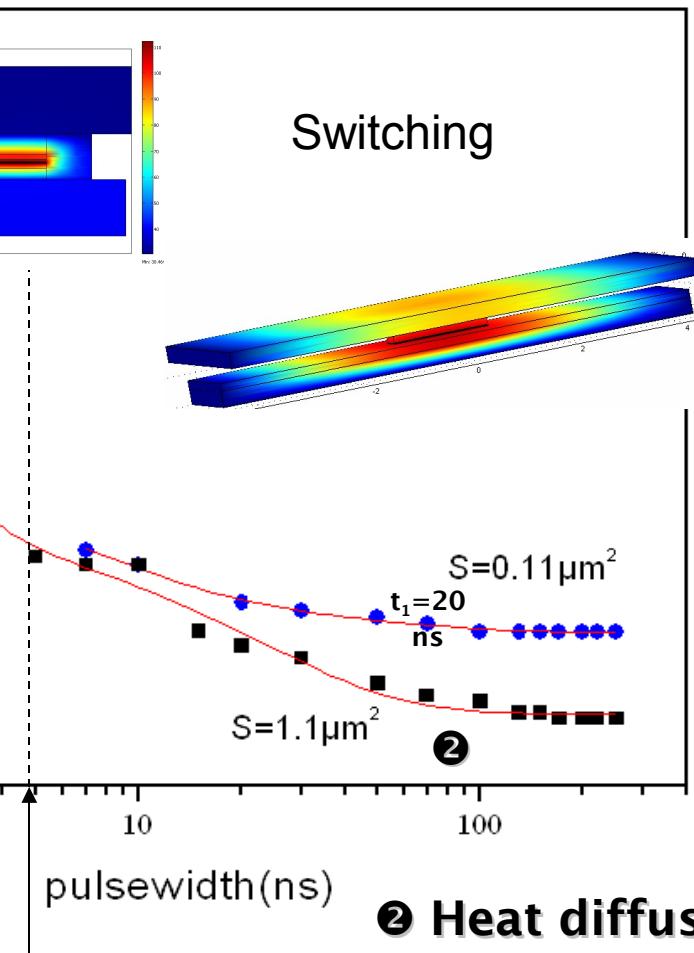
100nm  
MTJ pillar etched by RIE

 **CROCUS Technology**  
Blossoming Future

## ① Adiabatic heating of junction

$$E_{\text{write}} = C\Delta T \Rightarrow P_{\text{write}} = C\Delta T/t$$

Best operating region  
 $J_{\text{heating}} \sim 10^6 \text{ A/cm}^2$

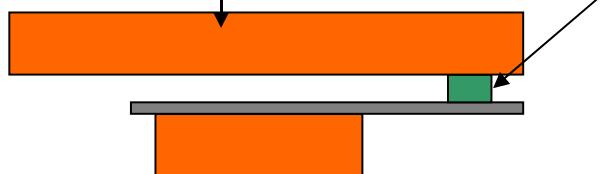


## ② Heat diffusion towards the leads

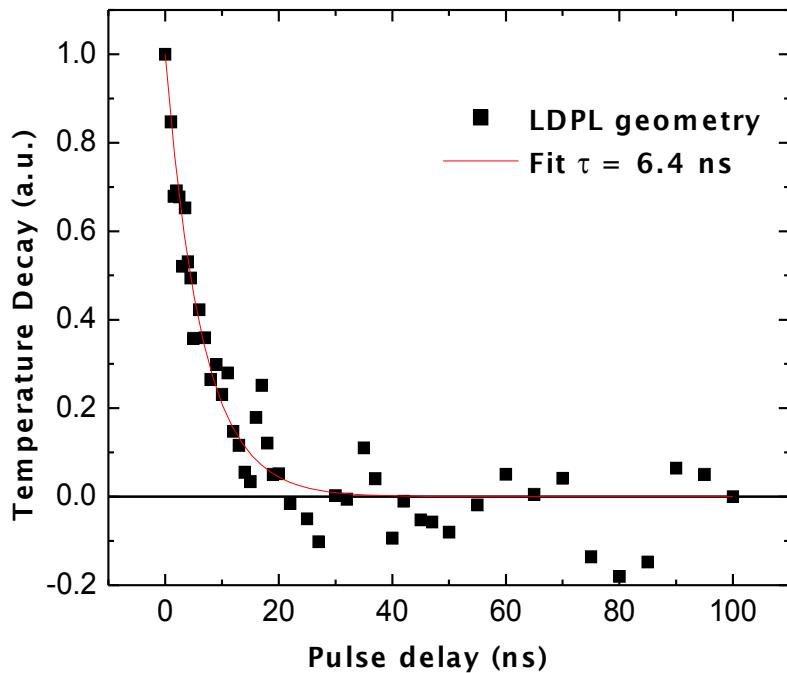
# Cooling dynamics in TA-MRAM

Bit line

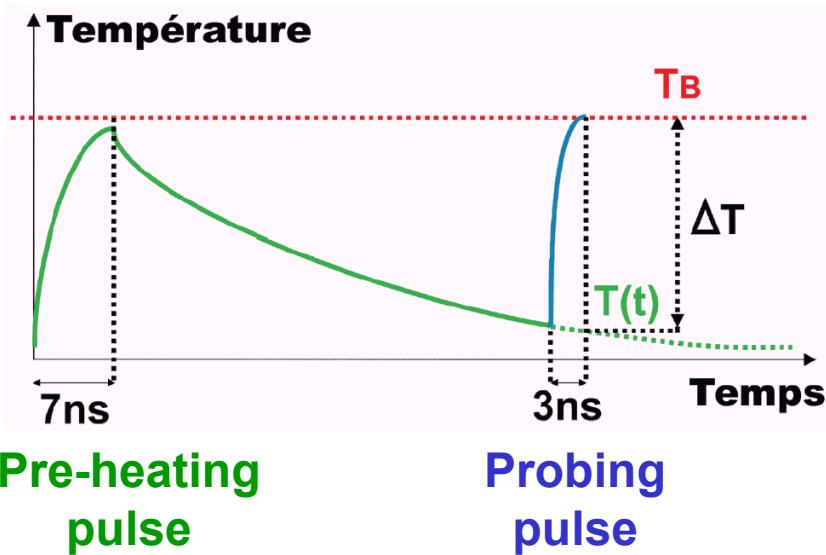
MTJ



Lot H343 - P25



Double-pulse method for measuring cooling dynamics (*C.Papusoi, J.Héault*):

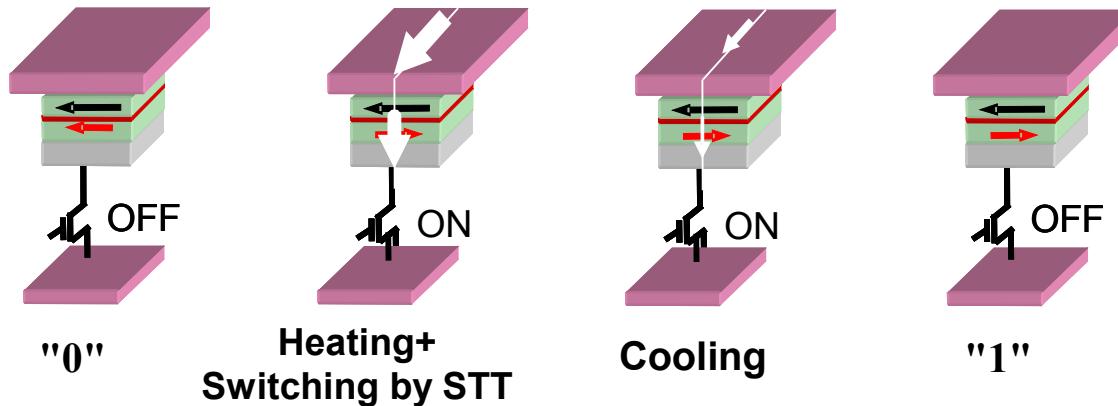


Characteristic cooling time~15ns.

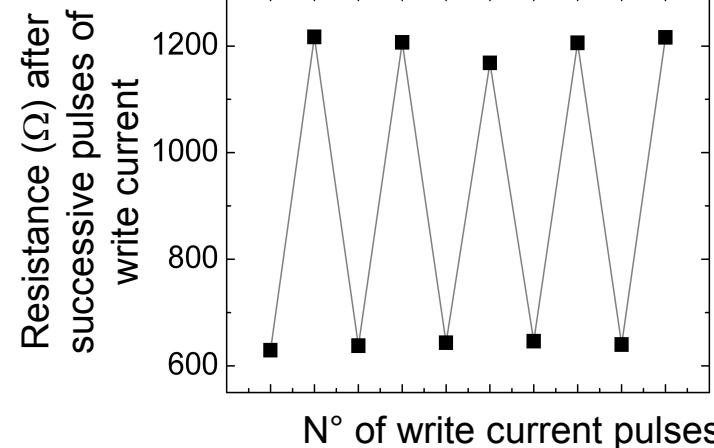
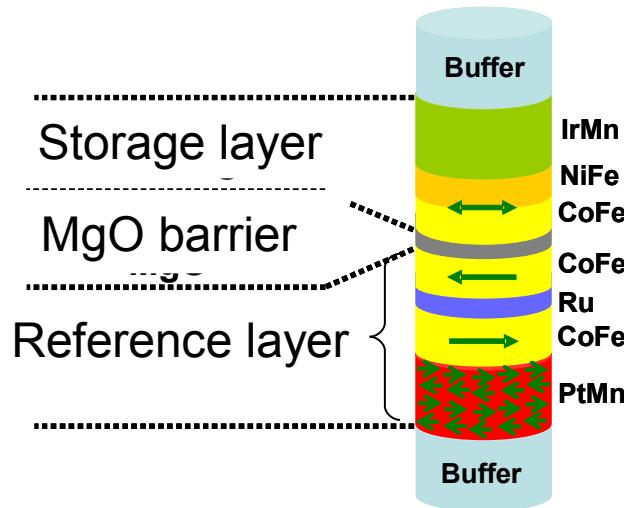
TA-MRAM cycle time ~30ns

# Combining spin-transfer with thermally assisted writing

The same bipolar current flowing through the cell is used to both temporarily heat the cell and apply a spin transfer torque to switch the magnetization of the storage layer.



## Experimental demonstration:



Approach offering the ultimate scalability (sub-15nm cell-size possible)  
With stability of information over 10 years.

# Scalability of TA-MRAM

## Heating+ pulse of magnetic field~2.5mT:

Scalability limited by electromigration in bit line (field generation) @ 45nm

## Heating+ STT:

Same bipolar CPP current used to heat and switch;

No Physical limit in downscaling from magnetic point of view down a few nm;

Can be implemented with :

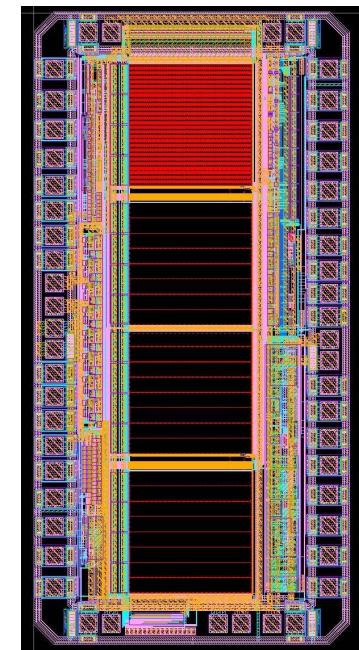
- in-plane magnetized material

(exchange biased storage layer)

- perpendicular-to-plane magnetized material

(variation of  $M_s$  or K with T)

*Layout of 1Mbit TA-MRAM demonstrator from Crocus Technology*

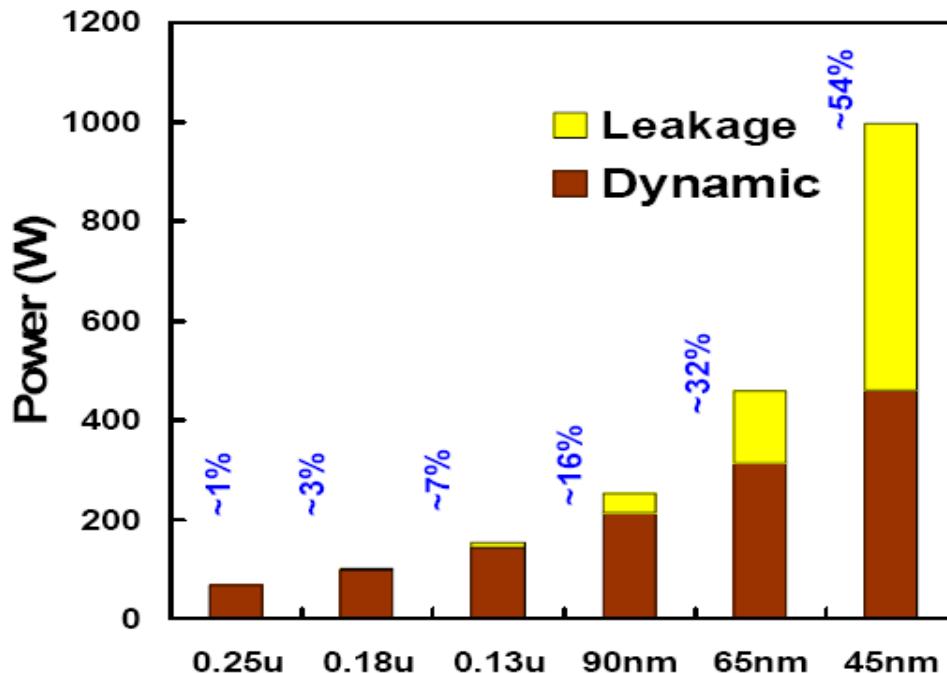


# New hybrid CMOS/MTJ architectures for non-volatile logic

DRAM, SRAM: volatile. Cannot be switched off without loosing information

However, increasing leakage current with downsizing (thinner gate oxide)

**Power consumption in  
CMOS electronic circuit  
per inch<sup>2</sup>**



Major benefit in introducing non-volatility in CMOS components in terms of energy savings

# Tighter integration between logic and memories

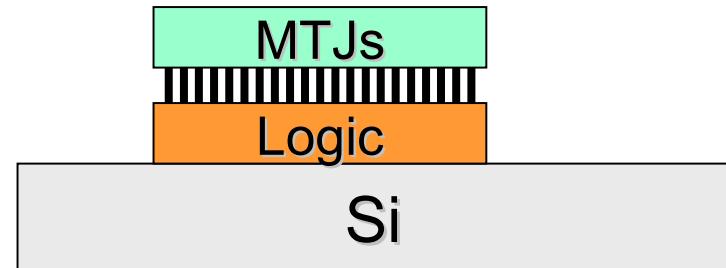
Same technology as for MRAM

Benefit from “Above IC” technology

With CMOS technology only:



With hybrid CMOS/magnetic:



Slow communication between  
logic and memory

- few long interconnections
- complexity of interconnecting paths
- larger occupancy on wafer

Non-volatility in logic

Large energy saving

- Fast communication between  
logic and memory
- numerous short vias
- simpler interconnecting paths
- Smaller occupancy on wafer

New paradigm for architecture of complex electronic circuit (microprocessors...)

# Magnetic Full Adder (Hitachi, Tohoku University)

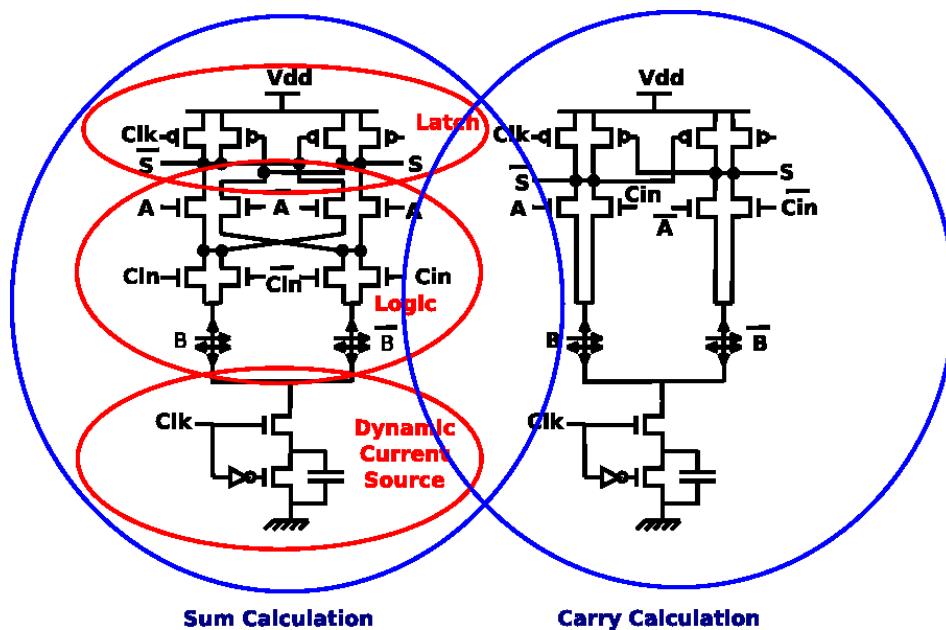
- Based on  
Dynamic Current Mode Logic
  - Dynamic consumption reduction
  - Footprint reduction

S.Matsunaga et al, *Applied Physics Express*, vol. 1, 2008.

## MTJs

- One input is made non-volatile (instant startup, security)
  - Drastic static consumption reduction
  - Footprint reduction
- Demonstrator : CMOS 0.18 $\mu$ m,
  - MTJs size: 200X100nm<sup>2</sup>

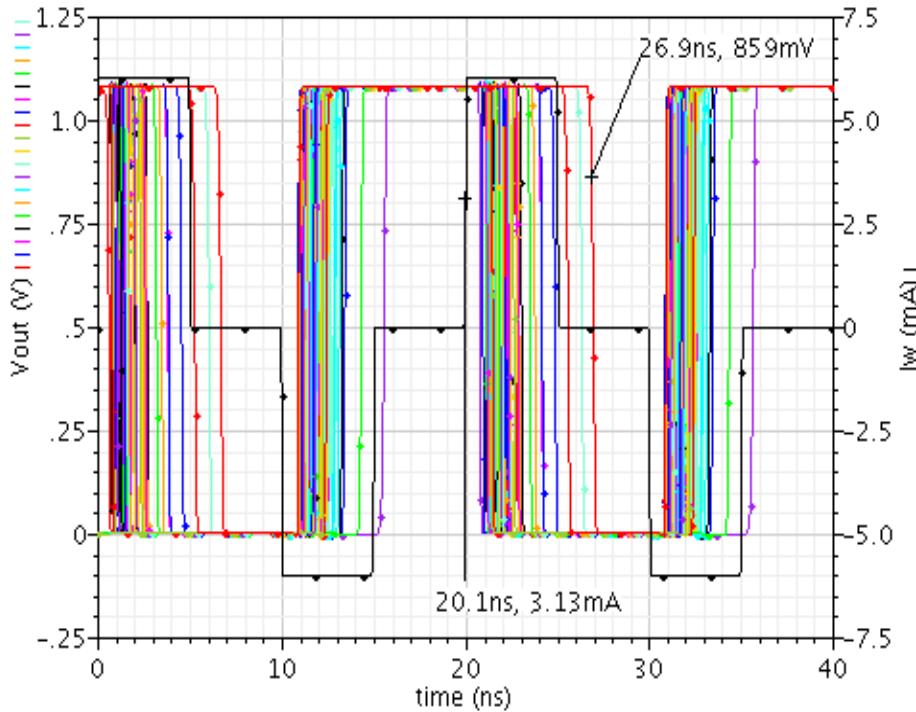
	CMOS	Hybrid
Delay	224 ps	219 ps
Dynamic Power	71.1 $\mu$ W	16.3 $\mu$ W
Writing Time	2 ns/bit	10 (2) ns/bit
Writing Energy	4 pJ/bit	20.9 (6.8) pJ/bit
Standby Power	0,9 nW	0 nW
Surface	333 $\mu$ m <sup>2</sup>	315 $\mu$ m <sup>2</sup>



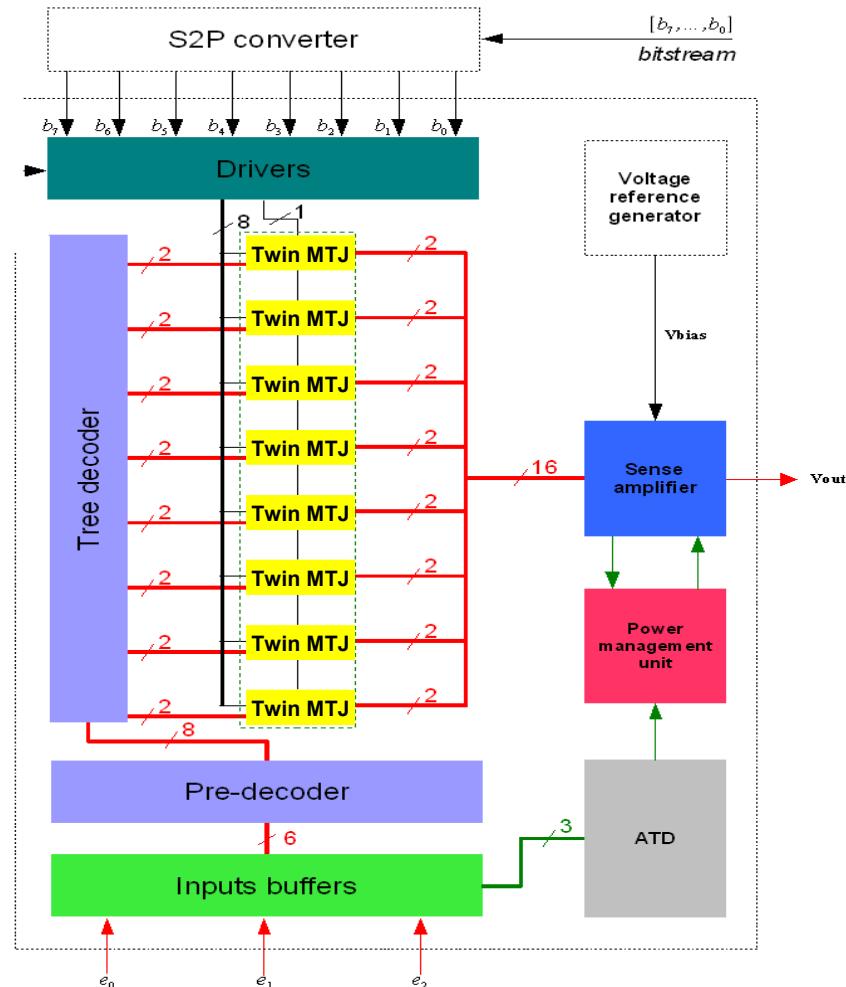
# Reprogrammable hybrid CMOS/MTJ logic gates

MTJ used as variable resistances to change the switching threshold of CMOS components

## Simulations of reprogrammability taking into account CMOS and magnetic process variations

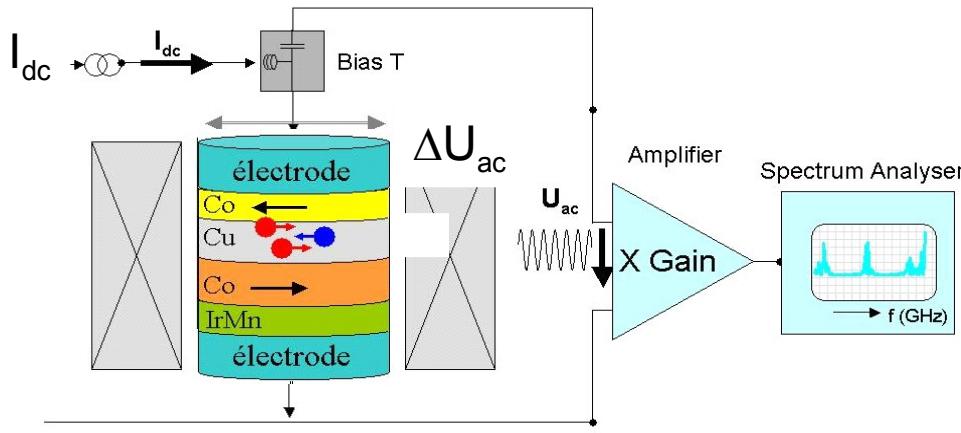


Extremely fast reprogramming



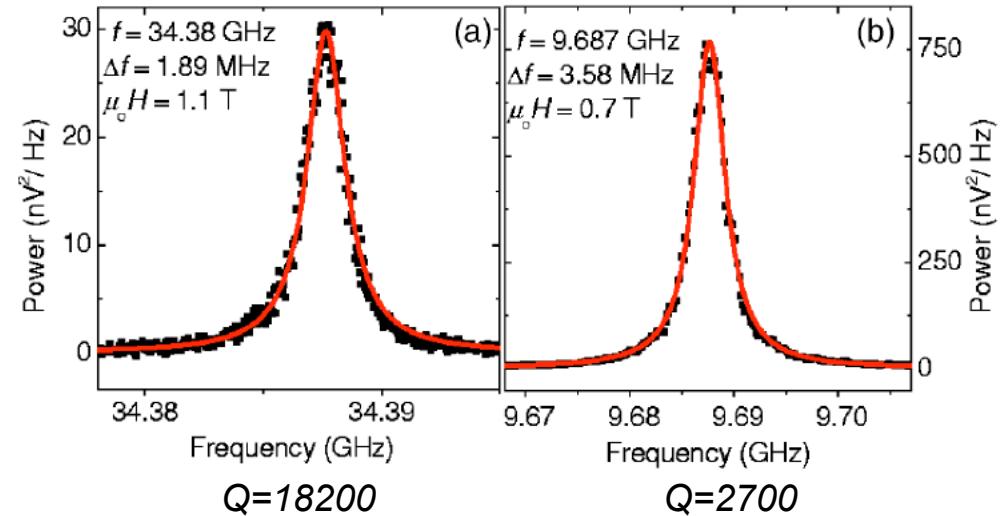
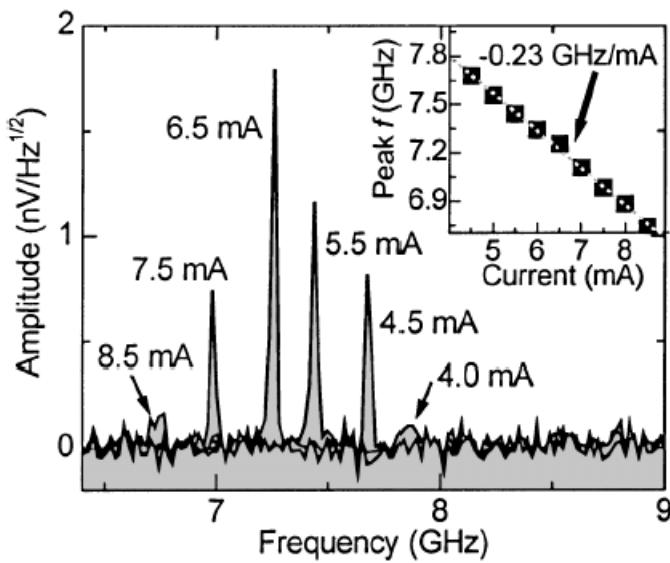
# RF components based on spin transfer

## Current Induced Steady State Oscillations

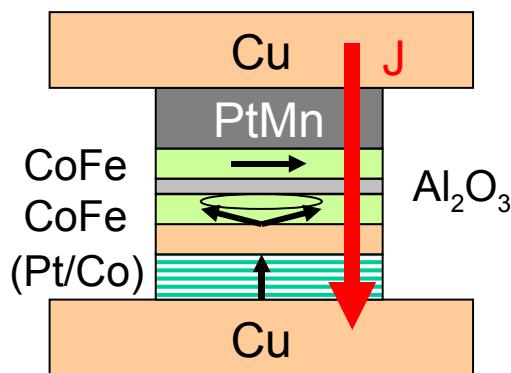


Kiselev et. al.,  
*Nature* **425**,  
p. 380 (2003)

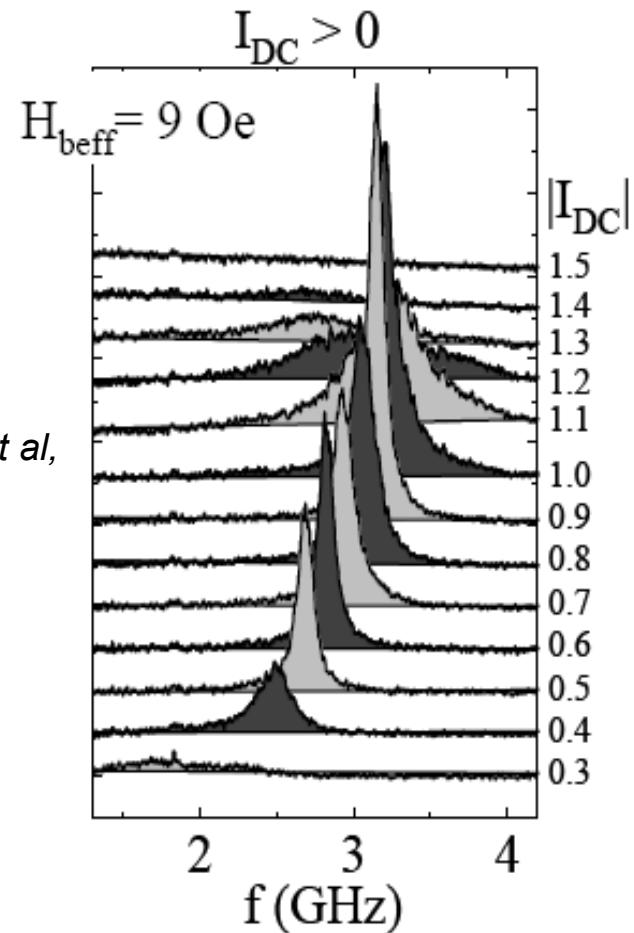
Rippard et. al.,  
*Phys. Rev. Lett.*  
**92**, p. 27201  
(2004)



# RF oscillator with perpendicular to plane polarizer



D.Houssamedine et al,  
Nat.Mat 2007

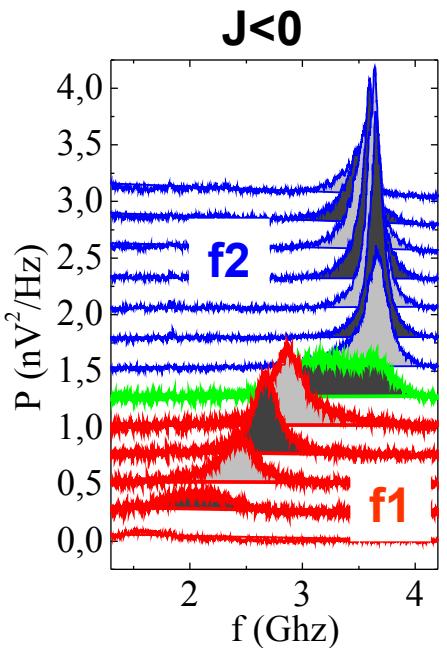


Injection of electrons with out-of-plane spins;  
Steady precession of the magnetization  
of the soft layer adjacent to the tunnel barrier.

Precession (2GHz-40GHz) + Tunnel MR  $\Rightarrow$  RF voltage  
Interesting for frequency tunable RF oscillators  $\Rightarrow$  Radio opportunism

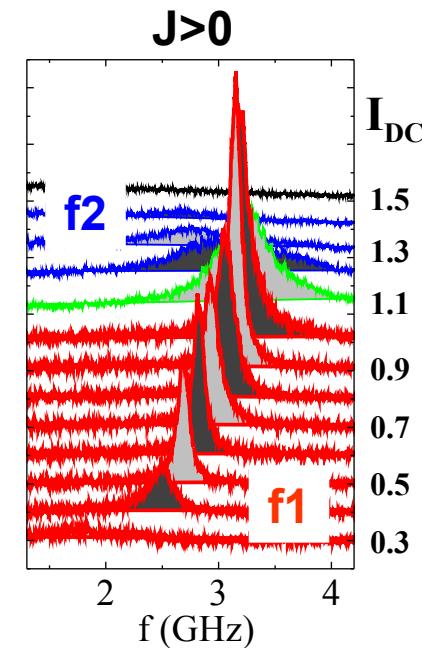
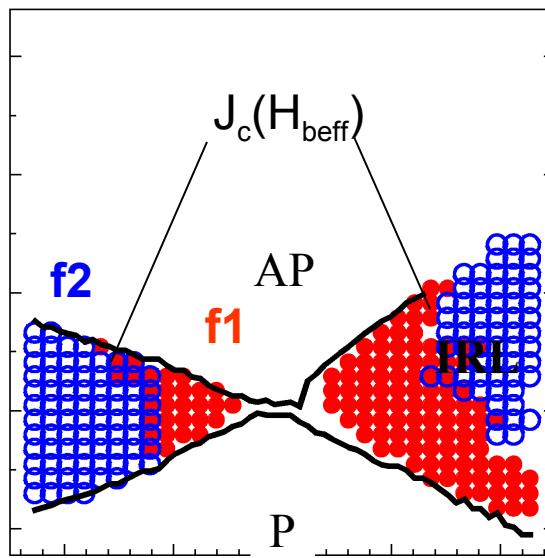
(SPINTEC patent + Lee et al, Appl.Phys.Lett.86, 022505 (2005) )

# Dynamic Spectra and Dynamic Diagram

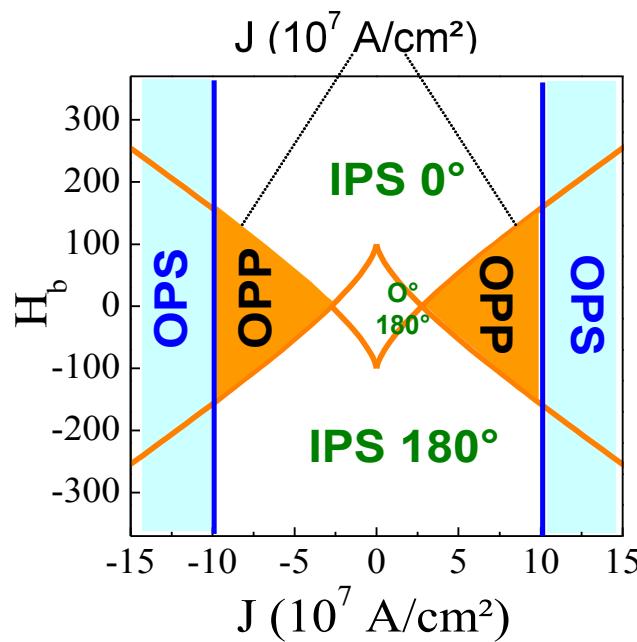


$H_{\text{beff}} = 9 \text{ Oe}$

D. Houssameddine et al.  
Nature Materials **6**, 447  
(2007)



$H_{\text{beff}} = 9 \text{ Oe}$

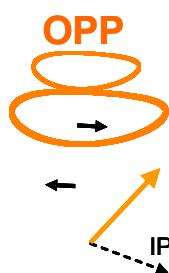


Macrospin simulated phase diagram calculated from LLG equation with spin-transfer term

# Micromagnetic simulations with perpendicular polarizer

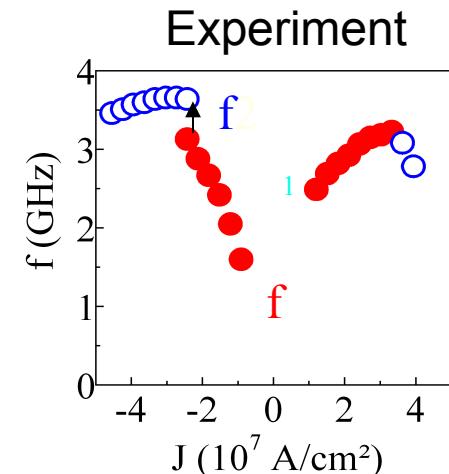
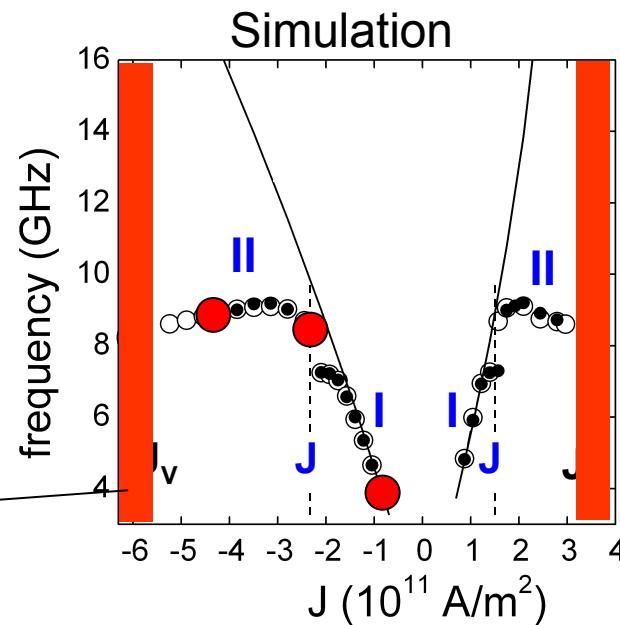
## Simulations\* for

- circular dot of 60 nm Ø
- $H_{\text{ext}} = 15 \text{ Oe}$ ,  $H_{\text{int}} = 0 \text{ Oe}$
- $\alpha = 0.01$

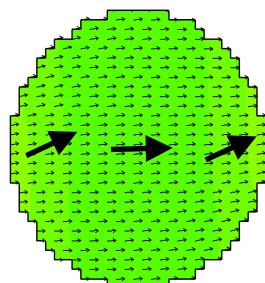


— Macrospin  
 ○ No  $H_{\text{ext}}$   
 ● With  $H_{\text{ext}}$

vortex



$M_z/M_s$   
 $J < J^*$   
 $-1.06 \cdot 10^7 \text{ A/cm}^2$

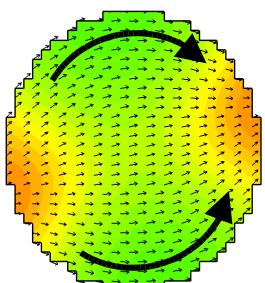


$H_{\text{ext}} = 0$

« S »

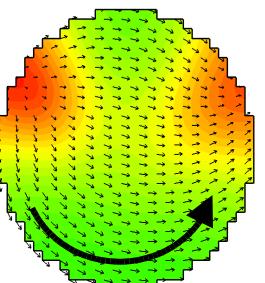
macrospin

$J > J^*$   
 $-3.2 \cdot 10^7 \text{ A/cm}^2$



« onion » distortion

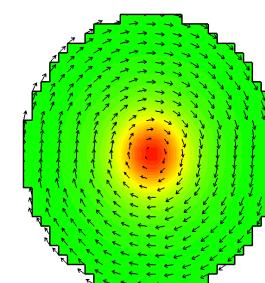
$J^* < J \leq J_v$   
 $-4.6 \cdot 10^7 \text{ A/cm}^2$



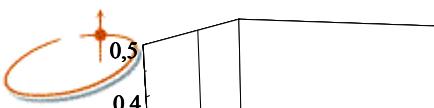
« C »

distortion

$J > J_v$   
 $< -5 \cdot 10^7 \text{ A/cm}^2$



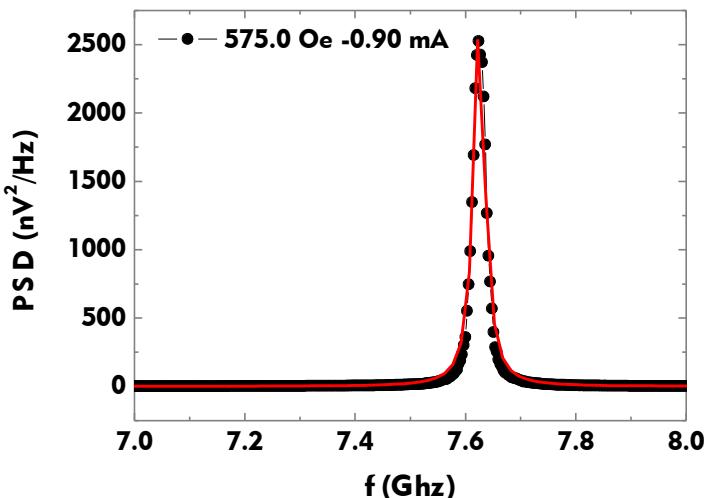
stable vortex



# Time domain versus spectral domain characterization of STT oscillators

## Spectral measurement

Several ms

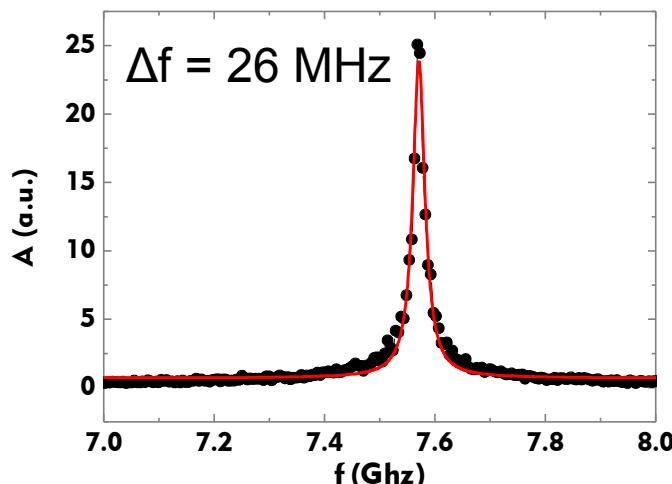
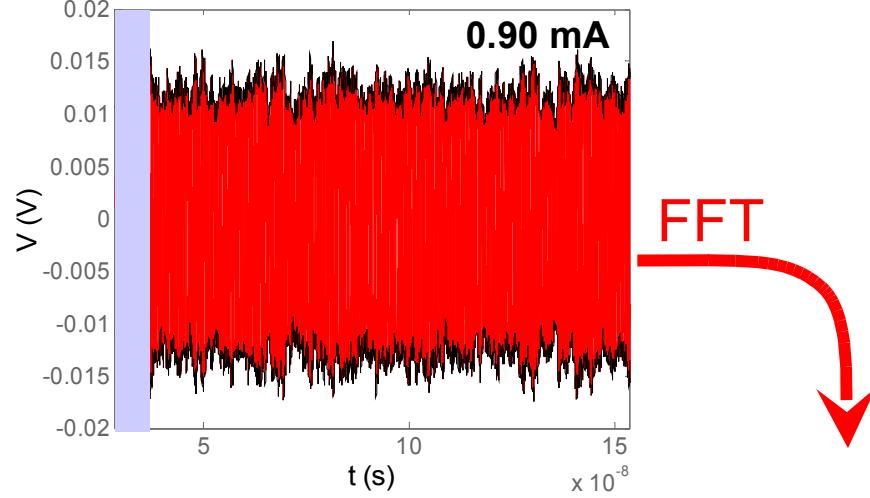


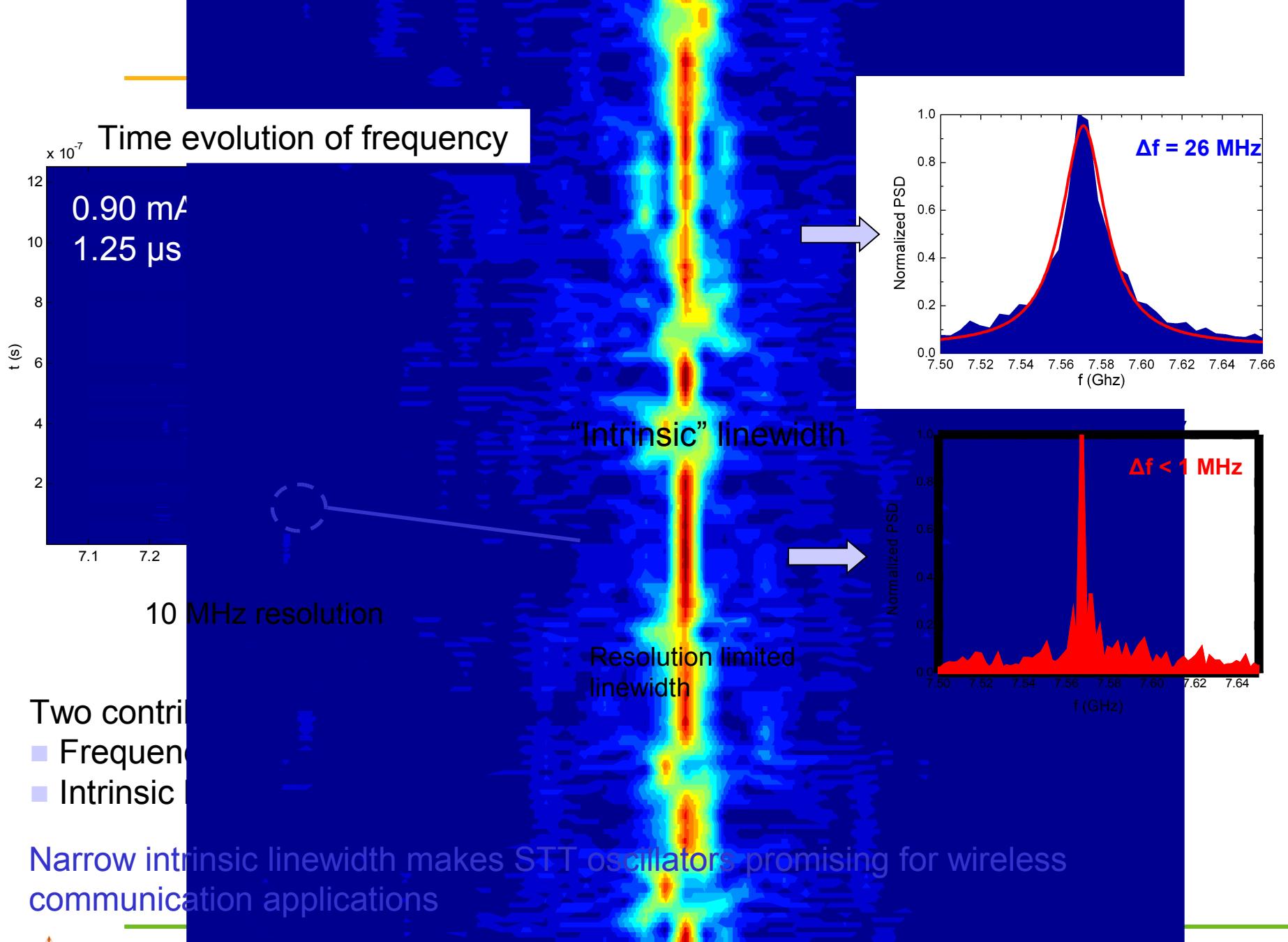
$$\Delta f = 25 \text{ MHz}$$

Spectrum analyzer linewidth = long time scale linewidth

## Time domain measurement

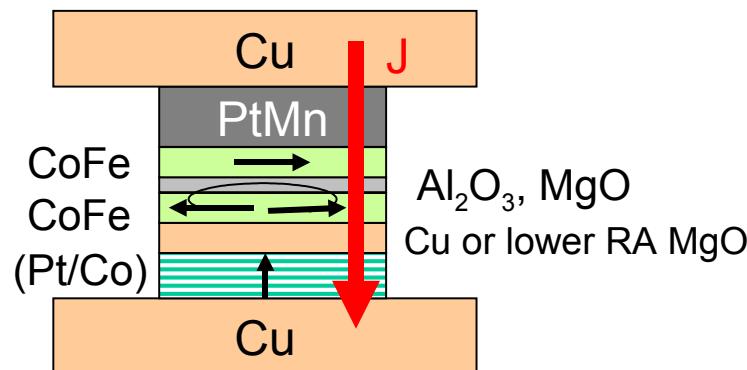
Few  $\mu\text{s}$



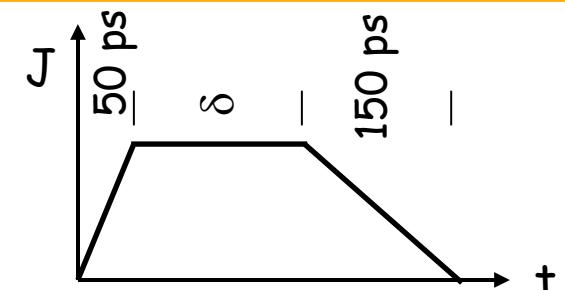


# Precessional switching in MRAM cell with perpendicular polarizer

MRAM cell:  
planar MTJ+perpendicular polarizer



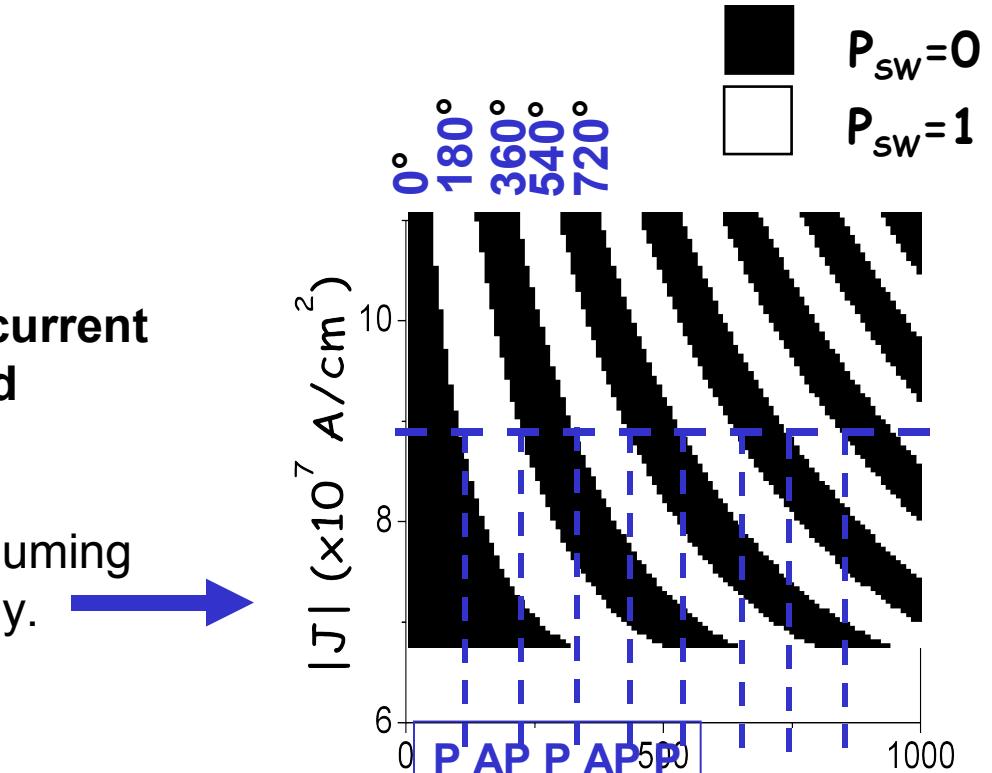
Current pulse  
shape



Switching by monopolar pulse of current  
of duration ~half precession period  
(30ps-300ps)

Macrospin LLG calculation at 0K assuming  
STT from perpendicular polarizer only.

70nm\*140nm elliptical , CoFe 3nm



Same pulse duration for  $P \Rightarrow AP$  and  $AP \Rightarrow P$

# Precessional switching in MRAM cell with perpendicular polarizer (cont'd)

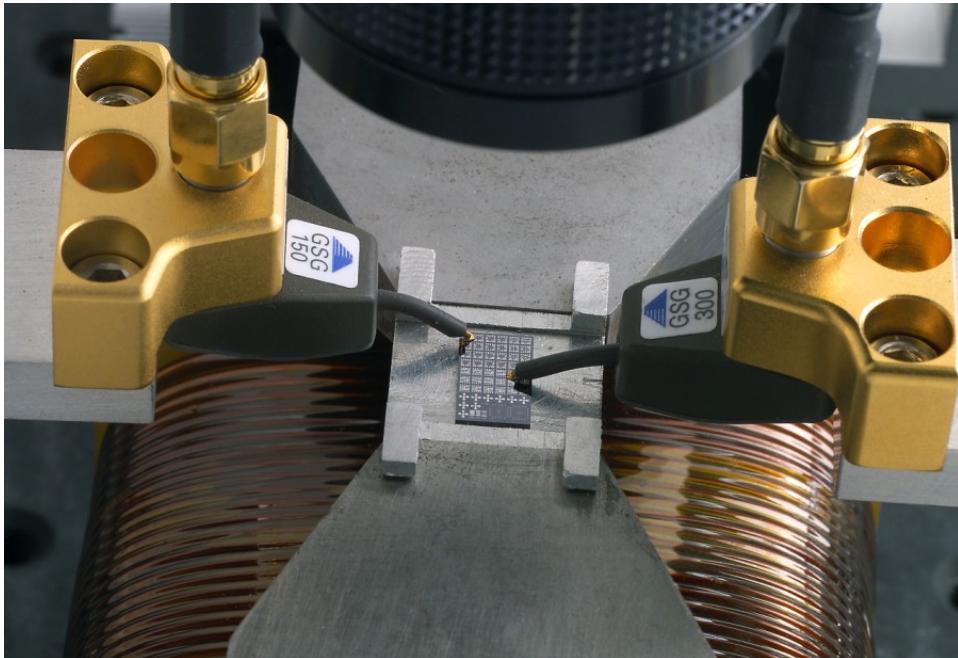
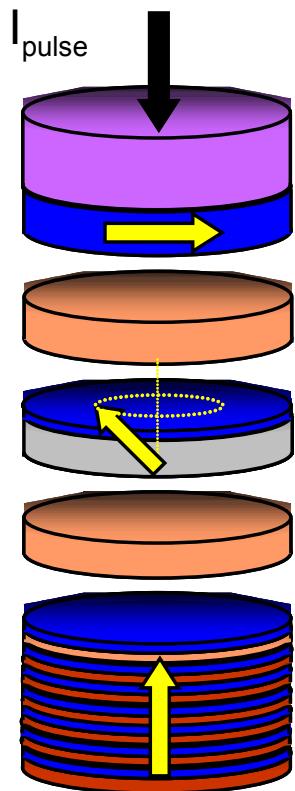
In-plane analyzer  
(Co/IrMn)

Metallic spacer (Cu)

Free layer (NiFe  
3/Co0.5nm)

Metallic spacer (Cu)

Perpendicular polarizer  
(Pt/[Co/Pt]<sub>n</sub>/Co/Cu/Co)

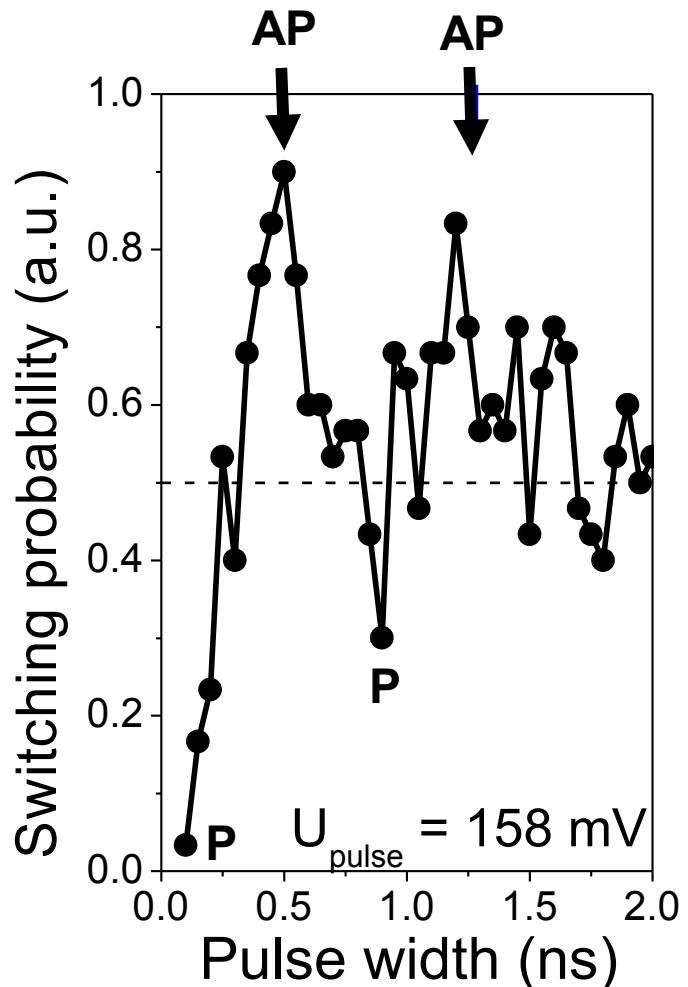


- Set a given configuration (P or AP)
- Apply a pulse of current of given amplitude and duration.
- Measure a posteriori the resistance of the stack to determine its magnetic state.
- Repeat 100 times for statistics of switching probability

# Precessional switching in MRAM cell with perpendicular polarizer (cont'd)

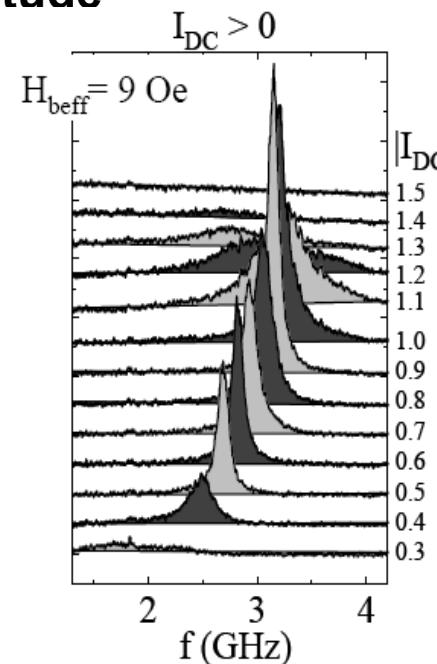
## Ultrafast switching at RT

Experiment repeated 100 times for each pulse width and amplitude



ellipse 200x100 nm  
 $\text{Ni}_{80}\text{Fe}_{20}$  3 / Co 0.5 nm

Switching in 400ps.  
Reasonable order of magnitude considering that precession frequency~2-3GHz



Damped oscillation in the switching probability at RT:  
-Influence of thermal fluctuations which induces a loss of coherence;  
-Influence of Oersted field during the current pulse

# Conclusion

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- GMR discovery has triggered the development of spin-electronics.  
Played a key role in magnetic recording and other sensor applications;
- Spin-valve magnetic concept (free/pinned by exchange anisotropy) also used in MTJ ⇒ Spin engineering;
- Spin-transfer offers a new way to manipulate the magnetization of magnetic nanostructures (switching, steady excitations)
- For CMOS/magnetic integration, MTJ offers more suitable impedance ~few  $k\Omega$  and larger magnetoresistance than GMR;
- Increasing interest for MRAM in microelectronics world;
- Besides MRAM, CMOS/MTJ integration quite interesting for logic, reprogrammable logic, innovative architecture.
- Frequency tunable RF oscillators interesting for wireless communications, RF interconnects.

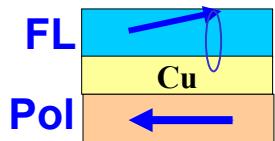
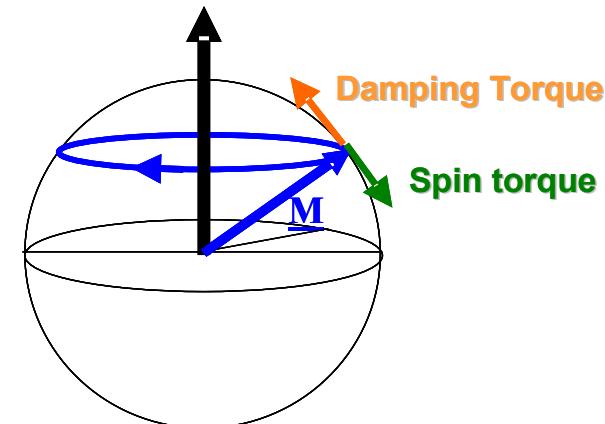
# Perpendicular versus Planar Polarizer

$$\frac{d\mathbf{M}}{dt} = -\gamma(\mathbf{M} \times \mathbf{H}_{eff}) + \frac{\alpha}{Ms}\mathbf{M} \times \frac{d\mathbf{M}}{dt} + \frac{\gamma a_J(\theta)}{Ms}\mathbf{M} \times (\mathbf{M} \times \mathbf{P})$$

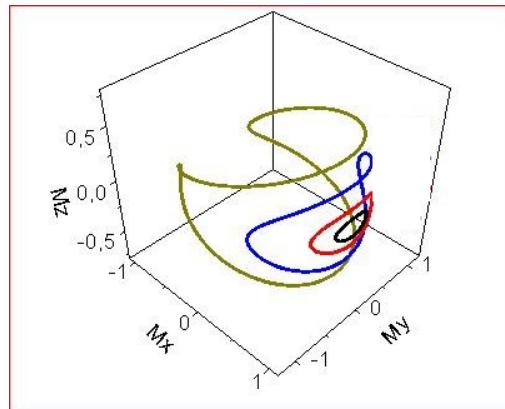
**Precession**

**Damping**

**Spin torque (ST)**

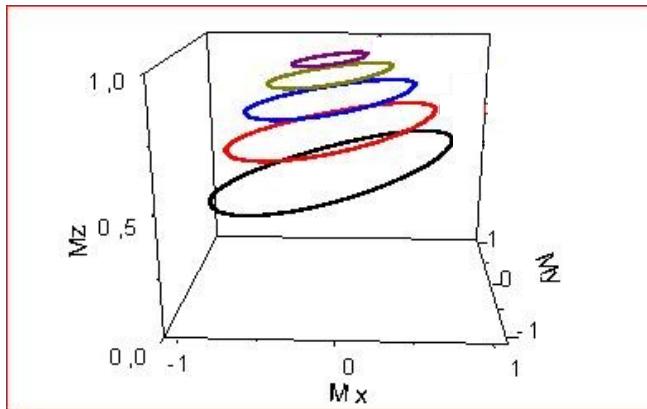


**In-Plane  
Precession IPP**

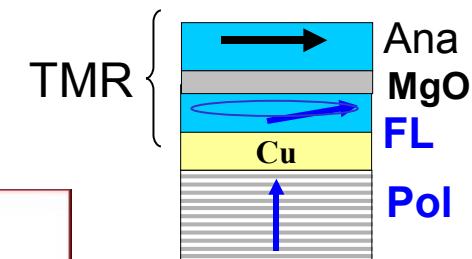


**Small angle precession  
around polarizer axis**

**Out-of-Plane  
Precession OPP**



**Large angle precession  
around out-of-plane axis**



- J. C. Slonczewski  
JMMM 157, (1996)
- O. Redon, B. Dieny  
US6,532,164 (2002)
- A. Kent et al.  
APL 84 (2004)
- K. J. Lee et al.  
APL 86 (2005)